Processing Data Where It Makes Sense in Modern Computing Systems: Enabling In-Memory Computation

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4 October 2018 HNEP 2018 Keynote

Systems @ ETH zürich





The Main Memory System



- Main memory is a critical component of all computing systems: server, mobile, embedded, desktop, sensor
- Main memory system must scale (in size, technology, efficiency, cost, and management algorithms) to maintain performance growth and technology scaling benefits

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Memory System: A *Shared Resource* View



Most of the system is dedicated to storing and moving data

State of the Main Memory System

- Recent technology, architecture, and application trends
 - lead to new requirements
 - exacerbate old requirements
- DRAM and memory controllers, as we know them today, are (will be) unlikely to satisfy all requirements
- Some emerging non-volatile memory technologies (e.g., PCM) enable new opportunities: memory+storage merging
- We need to rethink the main memory system
 to fix DRAM issues and enable emerging technologies
 to satisfy all requirements

Major Trends Affecting Main Memory (I)

Need for main memory capacity, bandwidth, QoS increasing

Main memory energy/power is a key system design concern

DRAM technology scaling is ending

Major Trends Affecting Main Memory (II)

- Need for main memory capacity, bandwidth, QoS increasing
 - Multi-core: increasing number of cores/agents
 - Data-intensive applications: increasing demand/hunger for data
 - Consolidation: cloud computing, GPUs, mobile, heterogeneity

• Main memory energy/power is a key system design concern

DRAM technology scaling is ending

Example: The Memory Capacity Gap

Core count doubling ~ every 2 years DRAM DIMM capacity doubling ~ every 3 years



Memory capacity per core expected to drop by 30% every two years
Trends worse for *memory bandwidth per core*!

Example: Capacity, Bandwidth & Latency



Memory latency remains almost constant

DRAM Latency Is Critical for Performance



In-memory Databases

[Mao+, EuroSys'12; Clapp+ (**Intel**), IISWC'15]



In-Memory Data Analytics

[Clapp+ (**Intel**), IISWC'15; Awan+, BDCloud'15]



Graph/Tree Processing [Xu+, IISWC'12; Umuroglu+, FPL'15]



Datacenter Workloads [Kanev+ (**Google**), ISCA'15]

DRAM Latency Is Critical for Performance





In-memory Databases

Graph/Tree Processing

Long memory latency → performance bottleneck



In-Memory Data Analytics

[Clapp+ (**Intel**), IISWC'15; Awan+, BDCloud'15]



Datacenter Workloads

[Kanev+ (Google), ISCA'I5]

Major Trends Affecting Main Memory (III)

Need for main memory capacity, bandwidth, QoS increasing

- Main memory energy/power is a key system design concern
 - ~40-50% energy spent in off-chip memory hierarchy [Lefurgy, IEEE Computer'03] >40% power in DRAM [Ware, HPCA'10][Paul,ISCA'15]
 - DRAM consumes power even when not used (periodic refresh)
- DRAM technology scaling is ending

Major Trends Affecting Main Memory (IV)

Need for main memory capacity, bandwidth, QoS increasing

Main memory energy/power is a key system design concern

DRAM technology scaling is ending

- ITRS projects DRAM will not scale easily below X nm
- Scaling has provided many benefits:
 - higher capacity (density), lower cost, lower energy

Major Trends Affecting Main Memory (V)

- DRAM scaling has already become increasingly difficult
 - Increasing cell leakage current, reduced cell reliability, increasing manufacturing difficulties [Kim+ ISCA 2014], [Liu+ ISCA 2013], [Mutlu IMW 2013], [Mutlu DATE 2017]
 - Difficult to significantly improve capacity, energy

Emerging memory technologies are promising

Major Trends Affecting Main Memory (V)

- DRAM scaling has already become increasingly difficult
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 - Difficult to significantly improve capacity, energy

Emerging memory technologies are promising

3D-Stacked DRAM	higher bandwidth	smaller capacity
Reduced-Latency DRAM (e.g., RL/TL-DRAM, FLY-RAM)	lower latency	higher cost
Low-Power DRAM (e.g., LPDDR3, LPDDR4, Voltron)	lower power	higher latency higher cost
Non-Volatile Memory (NVM) (e.g., PCM, STTRAM, ReRAM, 3D Xpoint)	larger capacity	higher latency higher dynamic power lower endurance

Major Trend: Hybrid Main Memory



Hardware/software manage data allocation and movement to achieve the best of multiple technologies

Meza+, "Enabling Efficient and Scalable Hybrid Memories," IEEE Comp. Arch. Letters, 2012. Yoon+, "Row Buffer Locality Aware Caching Policies for Hybrid Memories," ICCD 2012 Best Paper Award.



Main Memory Needs Intelligent Controllers

Industry Is Writing Papers About It, Too

DRAM Process Scaling Challenges

Refresh

- · Difficult to build high-aspect ratio cell capacitors decreasing cell capacitance
- · Leakage current of cell access transistors increasing

✤ tWR

- · Contact resistance between the cell capacitor and access transistor increasing
- · On-current of the cell access transistor decreasing
- · Bit-line resistance increasing

VRT

Occurring more frequently with cell capacitance decreasing



Call for Intelligent Memory Controllers

DRAM Process Scaling Challenges

* Refresh

Difficult to build high-aspect ratio cell capacitors decreasing cell capacitance
THE MEMORY FORUM 2014

Co-Architecting Controllers and DRAM to Enhance DRAM Process Scaling

Uksong Kang, Hak-soo Yu, Churoo Park, *Hongzhong Zheng, **John Halbert, **Kuljit Bains, SeongJin Jang, and Joo Sun Choi



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Samsung Electronics, Hwasung, Korea / *Samsung Electronics, San Jose / **Intel



- Major Trends Affecting Main Memory
- The Need for Intelligent Memory Controllers
 - Bottom Up: Push from Circuits and Devices
 - Top Down: Pull from Systems and Applications
- Processing in Memory: Two Directions
 - Minimally Changing Memory Chips
 - Exploiting 3D-Stacked Memory
- How to Enable Adoption of Processing in Memory
- Conclusion

Maslow's (Human) Hierarchy of Needs



We need to start with reliability and security...

How Reliable/Secure/Safe is This Bridge?



Collapse of the "Galloping Gertie"



How Secure Are These People?



Security is about preventing unforeseen consequences

Source: https://s-media-cache-ak0.pinimg.com/originals/48/09/54/4809543a9c7700246a0cf8acdae27abf.jpg

The DRAM Scaling Problem

- DRAM stores charge in a capacitor (charge-based memory)
 - Capacitor must be large enough for reliable sensing
 - Access transistor should be large enough for low leakage and high retention time
 - □ Scaling beyond 40-35nm (2013) is challenging [ITRS, 2009]



DRAM capacity, cost, and energy/power hard to scale

As Memory Scales, It Becomes Unreliable

- Data from all of Facebook's servers worldwide
- Meza+, "Revisiting Memory Errors in Large-Scale Production Data Centers," DSN'15.



Chip density (Gb)

Large-Scale Failure Analysis of DRAM Chips

- Analysis and modeling of memory errors found in all of Facebook's server fleet
- Justin Meza, Qiang Wu, Sanjeev Kumar, and Onur Mutlu, <u>"Revisiting Memory Errors in Large-Scale Production Data</u> <u>Centers: Analysis and Modeling of New Trends from the Field"</u> *Proceedings of the <u>45th Annual IEEE/IFIP International Conference on</u> <u>Dependable Systems and Networks</u> (DSN), Rio de Janeiro, Brazil, June 2015. [Slides (pptx) (pdf)] [DRAM Error Model]*

Revisiting Memory Errors in Large-Scale Production Data Centers: Analysis and Modeling of New Trends from the Field

Justin Meza Qiang Wu* Sanjeev Kumar* Onur Mutlu

Carnegie Mellon University * Facebook, Inc.

Infrastructures to Understand Such Issues



<u>Flipping Bits in Memory Without Accessing</u> <u>Them: An Experimental Study of DRAM</u> <u>Disturbance Errors</u> (Kim et al., ISCA 2014)

Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common-Case (Lee et al., HPCA 2015)

AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems (Qureshi et al., DSN 2015) An Experimental Study of Data Retention Behavior in Modern DRAM Devices: Implications for Retention Time Profiling Mechanisms (Liu et al., ISCA 2013)

The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study (Khan et al., SIGMETRICS 2014)



Infrastructures to Understand Such Issues



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Kim+, "Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors," ISCA 2014.

SoftMC: Open Source DRAM Infrastructure

 Hasan Hassan et al., "<u>SoftMC: A</u> <u>Flexible and Practical Open-</u> <u>Source Infrastructure for</u> <u>Enabling Experimental DRAM</u> <u>Studies</u>," HPCA 2017.

- Flexible
- Easy to Use (C++ API)
- Open-source

github.com/CMU-SAFARI/SoftMC





<u>https://github.com/CMU-SAFARI/SoftMC</u>

SoftMC: A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies

Hasan Hassan^{1,2,3} Nandita Vijaykumar³ Samira Khan^{4,3} Saugata Ghose³ Kevin Chang³ Gennady Pekhimenko^{5,3} Donghyuk Lee^{6,3} Oguz Ergin² Onur Mutlu^{1,3}

¹ETH Zürich ²TOBB University of Economics & Technology ³Carnegie Mellon University ⁴University of Virginia ⁵Microsoft Research ⁶NVIDIA Research

Data Retention in Memory [Liu et al., ISCA 2013]

Retention Time Profile of DRAM looks like this:

>256ms



64-128ms

Location dependent Stored value pattern dependent Time dependent

A Curious Discovery [Kim et al., ISCA 2014]

One can predictably induce errors in most DRAM memory chips

A simple hardware failure mechanism can create a widespread system security vulnerability



Modern DRAM is Prone to Disturbance Errors



Repeatedly reading a row enough times (before memory gets refreshed) induces disturbance errors in adjacent rows in most real DRAM chips you can buy today

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<u>Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM</u> <u>Disturbance Errors</u>, (Kim et al., ISCA 2014)
Most DRAM Modules Are Vulnerable









Up to	Up to	Up to
1.0×10 ⁷	2.7×10 ⁶	3.3×10 ⁵
errors	errors	errors

<u>Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM</u> <u>Disturbance Errors</u>, (Kim et al., ISCA 2014)

Recent DRAM Is More Vulnerable



Recent DRAM Is More Vulnerable



Recent DRAM Is More Vulnerable



All modules from 2012–2013 are vulnerable



loop: mov (X), %eax mov (Y), %ebx clflush (X) clflush (Y) mfence jmp loop





- Avoid *cache hits* Flush X from cache
- Avoid *row hits* to X
 Read Y in another row





loop: mov (X), %eax mov (Y), %ebx clflush (X) clflush (Y) mfence jmp loop





loop: mov (X), %eax mov (Y), %ebx clflush (X) clflush (Y) mfence jmp loop





loop: mov (X), %eax mov (Y), %ebx clflush (X) clflush (Y) mfence jmp loop



Observed Errors in Real Systems

CPU Architecture	Errors	Access-Rate
Intel Haswell (2013)	22 . 9K	12.3M/sec
Intel Ivy Bridge (2012)	20.7K	11.7M/sec
Intel Sandy Bridge (2011)	16.1K	11.6M/sec
AMD Piledriver (2012)	59	6.1M/sec

A real reliability & security issue

Kim+, "Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors," ISCA 2014.

One Can Take Over an Otherwise-Secure System

Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Abstract. Memory isolation is a key property of a reliable and secure computing system — an access to one memory address should not have unintended side effects on data stored in other addresses. However, as DRAM process technology

Project Zero

Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors (Kim et al., ISCA 2014)

News and updates from the Project Zero team at Google

Exploiting the DRAM rowhammer bug to gain kernel privileges (Seaborn, 2015)

Monday, March 9, 2015

Exploiting the DRAM rowhammer bug to gain kernel privileges

RowHammer Security Attack Example

- "Rowhammer" is a problem with some recent DRAM devices in which repeatedly accessing a row of memory can cause bit flips in adjacent rows (Kim et al., ISCA 2014).
 - Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors (Kim et al., ISCA 2014)
- We tested a selection of laptops and found that a subset of them exhibited the problem.
- We built two working privilege escalation exploits that use this effect.
 - Exploiting the DRAM rowhammer bug to gain kernel privileges (Seaborn+, 2015)
- One exploit uses rowhammer-induced bit flips to gain kernel privileges on x86-64 Linux when run as an unprivileged userland process.
- When run on a machine vulnerable to the rowhammer problem, the process was able to induce bit flips in page table entries (PTEs).
- It was able to use this to gain write access to its own page table, and hence gain read-write access to all of physical memory.

Exploiting the DRAM rowhammer bug to gain kernel privileges (Seaborn & Dullien, 2015)

Security Implications



Security Implications



It's like breaking into an apartment by repeatedly slamming a neighbor's door until the vibrations open the door you were after

More Security Implications (I)

"We can gain unrestricted access to systems of website visitors."

Not there yet, but ...



ROOT privileges for web apps!

Daniel Gruss (@lavados), Clémentine Maurice (@BloodyTangerine), December 28, 2015 - 32c3, Hamburg, Germany



www.iaik.tugraz.at



Rowhammer.js: A Remote Software-Induced Fault Attack in JavaScript (DIMVA'16)

Source: https://lab.dsst.io/32c3-slides/7197.html

More Security Implications (II)

"Can gain control of a smart phone deterministically"

Hammer And Root

androids Millions of Androids

Drammer: Deterministic Rowhammer Attacks on Mobile Platforms, CCS'16 52

Source: https://fossbytes.com/drammer-rowhammer-attack-android-root-devices/

More Security Implications (III)

 Using an integrated GPU in a mobile system to remotely escalate privilege via the WebGL interface

ars technica

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Drive-by Rowhammer attack uses GPU to compromise an Android phone

JavaScript based GLitch pwns browsers by flipping bits inside memory chips.

DAN GOODIN - 5/3/2018, 12:00 PM

Grand Pwning Unit: Accelerating Microarchitectural Attacks with the GPU

Pietro Frigo Vrije Universiteit Amsterdam p.frigo@vu.nl Cristiano Giuffrida Vrije Universiteit Amsterdam giuffrida@cs.vu.nl Herbert Bos Vrije Universiteit Amsterdam herbertb@cs.vu.nl Kaveh Razavi Vrije Universiteit Amsterdam kaveh@cs.vu.nl

More Security Implications (IV)

Rowhammer over RDMA (I)

ars TECHNICA

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THROWHAMMER —

Packets over a LAN are all it takes to trigger serious Rowhammer bit flips

The bar for exploiting potentially serious DDR weakness keeps getting lower.

DAN GOODIN - 5/10/2018, 5:26 PM

Throwhammer: Rowhammer Attacks over the Network and Defenses

Andrei Tatar VU Amsterdam Radhesh Krishnan VU Amsterdam

> Herbert Bos VU Amsterdam

Elias Athanasopoulos University of Cyprus

> Kaveh Razavi VU Amsterdam

Cristiano Giuffrida VU Amsterdam

More Security Implications (V)

Rowhammer over RDMA (II)

Security in a serious way

Nethammer—Exploiting DRAM Rowhammer Bug Through Network Requests



Nethammer: Inducing Rowhammer Faults through Network Requests

Moritz Lipp Graz University of Technology

Daniel Gruss Graz University of Technology Misiker Tadesse Aga University of Michigan

Clémentine Maurice Univ Rennes, CNRS, IRISA

Lukas Lamster Graz University of Technology Michael Schwarz Graz University of Technology

Lukas Raab Graz University of Technology

More Security Implications?



Apple's Patch for RowHammer

https://support.apple.com/en-gb/HT204934

Available for: OS X Mountain Lion v10.8.5, OS X Mavericks v10.9.5

Impact: A malicious application may induce memory corruption to escalate privileges

Description: A disturbance error, also known as Rowhammer, exists with some DDR3 RAM that could have led to memory corruption. This issue was mitigated by increasing memory refresh rates.

CVE-ID

CVE-2015-3693 : Mark Seaborn and Thomas Dullien of Google, working from original research by Yoongu Kim et al (2014)

HP, Lenovo, and other vendors released similar patches

Our Solution to RowHammer

- PARA: <u>Probabilistic Adjacent Row Activation</u>
- Key Idea
 - After closing a row, we activate (i.e., refresh) one of its neighbors with a low probability: p = 0.005
- Reliability Guarantee
 - When p=0.005, errors in one year: 9.4×10^{-14}
 - By adjusting the value of p, we can vary the strength of protection against errors

Advantages of PARA

- PARA refreshes rows infrequently
 - Low power
 - Low performance-overhead
 - Average slowdown: 0.20% (for 29 benchmarks)
 - Maximum slowdown: 0.75%
- PARA is stateless
 - Low cost
 - Low complexity
- PARA is an effective and low-overhead solution to prevent disturbance errors

Probabilistic Activation in Real Life (I)

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https://twitter.com/isislovecruft/status/1021939922754723841

Probabilistic Activation in Real Life (II)



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https://twitter.com/isislovecruft/status/1021939922754723841

More on RowHammer Analysis

Yoongu Kim, Ross Daly, Jeremie Kim, Chris Fallin, Ji Hye Lee, Donghyuk Lee, Chris Wilkerson, Konrad Lai, and Onur Mutlu,
 "Flipping Bits in Memory Without Accessing Them: An

 Experimental Study of DRAM Disturbance Errors"
 Proceedings of the <u>41st International Symposium on Computer</u>
 <u>Architecture</u> (ISCA), Minneapolis, MN, June 2014.

 [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)] [Source Code and Data]

Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Yoongu Kim¹ Ross Daly^{*} Jeremie Kim¹ Chris Fallin^{*} Ji Hye Lee¹ Donghyuk Lee¹ Chris Wilkerson² Konrad Lai Onur Mutlu¹ ¹Carnegie Mellon University ²Intel Labs

Future of Memory Reliability

Onur Mutlu, "The RowHammer Problem and Other Issues We May Face as Memory Becomes Denser" Invited Paper in Proceedings of the Design, Automation, and Test in Europe Conference (DATE), Lausanne, Switzerland, March 2017. [Slides (pptx) (pdf)]

The RowHammer Problem and Other Issues We May Face as Memory Becomes Denser

Onur Mutlu ETH Zürich onur.mutlu@inf.ethz.ch https://people.inf.ethz.ch/omutlu

SAFARI https://people.inf.ethz.ch/omutlu/pub/rowhammer-and-other-memory-issues_date17.pdf 63

Industry Is Writing Papers About It, Too

DRAM Process Scaling Challenges

* Refresh

- · Difficult to build high-aspect ratio cell capacitors decreasing cell capacitance
- · Leakage current of cell access transistors increasing

✤ tWR

- · Contact resistance between the cell capacitor and access transistor increasing
- · On-current of the cell access transistor decreasing
- · Bit-line resistance increasing

VRT

Occurring more frequently with cell capacitance decreasing



Call for Intelligent Memory Controllers

DRAM Process Scaling Challenges

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Samsung Electronics, Hwasung, Korea / *Samsung Electronics, San Jose / **Intel

Aside: Intelligent Controller for NAND Flash



[DATE 2012, ICCD 2012, DATE 2013, ITJ 2013, ICCD 2013, SIGMETRICS 2014, HPCA 2015, DSN 2015, MSST 2015, JSAC 2016, HPCA 2017, DFRWS 2017, PIEEE 2017, HPCA 2018, SIGMETRICS 2018]

NAND Daughter Board

Cai+, "Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives," Proc. IEEE 2017.

Aside: Intelligent Controller for NAND Flash



Proceedings of the IEEE, Sept. 2017

Error Characterization, Mitigation, and Recovery in Flash-Memory-Based Solid-State Drives



This paper reviews the most recent advances in solid-state drive (SSD) error characterization, mitigation, and data recovery techniques to improve both SSD's reliability and lifetime.

By Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu

https://arxiv.org/pdf/1706.08642



Main Memory Needs Intelligent Controllers



- Major Trends Affecting Main Memory
- The Need for Intelligent Memory Controllers
 - Bottom Up: Push from Circuits and Devices
 - Top Down: Pull from Systems and Applications
- Processing in Memory: Two Directions
 - Minimally Changing Memory Chips
 - Exploiting 3D-Stacked Memory
- How to Enable Adoption of Processing in Memory
- Conclusion

1. Data access is a major bottleneck

Applications are increasingly data hungry

2. Energy consumption is a key limiter

3. Data movement energy dominates computeEspecially true for off-chip to on-chip movement

The Need for More Memory Performance



In-memory Databases

[Mao+, EuroSys'12; Clapp+ (**Intel**), IISWC'15]



In-Memory Data Analytics

[Clapp+ (**Intel**), IISWC'15; Awan+, BDCloud'15]



Graph/Tree Processing [Xu+, IISWC'12; Umuroglu+, FPL'15]



Datacenter Workloads [Kanev+ (**Google**), ISCA'15]

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Do We Want This?



SAFARI Source: V. Milutinovic
Or This?



SAFARI Source:

Maslow's (Human) Hierarchy of Needs, Revisited



Challenge and Opportunity for Future

High Performance, Energy Efficient, Sustainable

Data access is the major performance and energy bottleneck

Our current design principles cause great energy waste (and great performance loss)

Processing of data is performed far away from the data

A Computing System

- Three key components
- Computation
- Communication
- Storage/memory



Burks, Goldstein, von Neumann, "Preliminary discussion of the logical design of an electronic computing instrument," 1946.

Computing System



A Computing System

- Three key components
- Computation
- Communication
- Storage/memory



Burks, Goldstein, von Neumann, "Preliminary discussion of the logical design of an electronic computing instrument," 1946.

Computing System



Image source: https://lbsitbytes2010.wordpress.com/2013/03/29/john-von-neumann-roll-no-15/

Today's Computing Systems

- Are overwhelmingly processor centric
- All data processed in the processor \rightarrow at great system cost
- Processor is heavily optimized and is considered the master
- Data storage units are dumb and are largely unoptimized (except for some that are on the processor die)



Yet ...

"It's the Memory, Stupid!" (Richard Sites, MPR, 1996)



Mutlu+, "Runahead Execution: An Alternative to Very Large Instruction Windows for Out-of-Order Processors," HPCA 2003.

The Performance Perspective

 Onur Mutlu, Jared Stark, Chris Wilkerson, and Yale N. Patt, "Runahead Execution: An Alternative to Very Large Instruction Windows for Out-of-order Processors" Proceedings of the <u>9th International Symposium on High-Performance</u> <u>Computer Architecture</u> (HPCA), pages 129-140, Anaheim, CA, February 2003. <u>Slides (pdf)</u>

Runahead Execution: An Alternative to Very Large Instruction Windows for Out-of-order Processors

Onur Mutlu § Jared Stark † Chris Wilkerson ‡ Yale N. Patt §

§ECE Department The University of Texas at Austin {onur,patt}@ece.utexas.edu †Microprocessor Research Intel Labs jared.w.stark@intel.com

‡Desktop Platforms Group Intel Corporation chris.wilkerson@intel.com

The Performance Perspective (Today)

All of Google's Data Center Workloads (2015):



Kanev+, "Profiling a Warehouse-Scale Computer," ISCA 2015.

The Performance Perspective (Today)

All of Google's Data Center Workloads (2015):



Figure 11: Half of cycles are spent stalled on caches.

Perils of Processor-Centric Design

Grossly-imbalanced systems

- Processing done only in **one place**
- Everything else just stores and moves data: data moves a lot
- \rightarrow Energy inefficient
- \rightarrow Low performance
- \rightarrow Complex
- Overly complex and bloated processor (and accelerators)
 - To tolerate data access from memory
 - Complex hierarchies and mechanisms
 - \rightarrow Energy inefficient
 - \rightarrow Low performance
 - \rightarrow Complex

Perils of Processor-Centric Design



Most of the system is dedicated to storing and moving data

The Energy Perspective



Data Movement vs. Computation Energy



A memory access consumes ~1000X the energy of a complex addition

Data Movement vs. Computation Energy

Data movement is a major system energy bottleneck

- Comprises 41% of mobile system energy during web browsing [2]
- Costs ~115 times as much energy as an ADD operation [1, 2]



[1]: Reducing data Movement Energy via Online Data Clustering and Encoding (MICRO'16)

[2]: Quantifying the energy cost of data movement for emerging smart phone workloads on mobile platforms (IISWC'14)

Energy Waste in Mobile Devices

 Amirali Boroumand, Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, and Onur Mutlu, "Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks" Proceedings of the <u>23rd International Conference on Architectural Support for Programming</u> <u>Languages and Operating Systems</u> (ASPLOS), Williamsburg, VA, USA, March 2018.

62.7% of the total system energy is spent on data movement

Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand¹Saugata Ghose¹Youngsok Kim²Rachata Ausavarungnirun¹Eric Shiu³Rahul Thakur³Daehyun Kim^{4,3}Aki Kuusela³Allan Knies³Parthasarathy Ranganathan³Onur Mutlu^{5,1}90

We Do Not Want to Move Data!



A memory access consumes ~1000X the energy of a complex addition

We Need A Paradigm Shift To ...

Enable computation with minimal data movement

Compute where it makes sense (where data resides)

Make computing architectures more data-centric

Goal: Processing Inside Memory



Why In-Memory Computation Today?

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- Data access is a major system and application bottleneck
- Systems are energy limited
- Data movement much more energy-hungry than computation

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Dally, Midead

AUTOMAT



- Major Trends Affecting Main Memory
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Processing in Memory: Two Approaches

Minimally changing memory chips
Exploiting 3D-stacked memory

Approach 1: Minimally Changing DRAM

- DRAM has great capability to perform bulk data movement and computation internally with small changes
 - Can exploit internal connectivity to move data
 - Can exploit analog computation capability

• Examples: RowClone, In-DRAM AND/OR, Gather/Scatter DRAM

- <u>RowClone: Fast and Efficient In-DRAM Copy and Initialization of Bulk Data</u> (Seshadri et al., MICRO 2013)
- □ Fast Bulk Bitwise AND and OR in DRAM (Seshadri et al., IEEE CAL 2015)
- <u>Gather-Scatter DRAM: In-DRAM Address Translation to Improve the Spatial</u> <u>Locality of Non-unit Strided Accesses</u> (Seshadri et al., MICRO 2015)
- "Ambit: In-Memory Accelerator for Bulk Bitwise Operations Using Commodity DRAM Technology" (Seshadri et al., MICRO 2017)

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Starting Simple: Data Copy and Initialization

memmove & memcpy: 5% cycles in Google's datacenter [Kanev+ ISCA'15]





VM Cloning Deduplication



••• Many more

Page Migration

Today's Systems: Bulk Data Copy



Future Systems: In-Memory Copy



RowClone: In-DRAM Row Copy



Data Bus

RowClone: Latency and Energy Savings



Seshadri et al., "RowClone: Fast and Efficient In-DRAM Copy and Initialization of Bulk Data," MICRO 2013.

More on RowClone

 Vivek Seshadri, Yoongu Kim, Chris Fallin, Donghyuk Lee, Rachata Ausavarungnirun, Gennady Pekhimenko, Yixin Luo, Onur Mutlu, Michael A. Kozuch, Phillip B. Gibbons, and Todd C. Mowry, "RowClone: Fast and Energy-Efficient In-DRAM Bulk Data Copy and Initialization" Proceedings of the <u>46th International Symposium on Microarchitecture</u>

(*MICRO*), Davis, CA, December 2013. [<u>Slides (pptx) (pdf)</u>] [<u>Lightning Session</u> <u>Slides (pptx) (pdf)</u>] [<u>Poster (pptx) (pdf)</u>]

RowClone: Fast and Energy-Efficient In-DRAM Bulk Data Copy and Initialization

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Memory as an Accelerator



Memory similar to a "conventional" accelerator

In-Memory Bulk Bitwise Operations

- We can support in-DRAM COPY, ZERO, AND, OR, NOT, MAJ
- At low cost
- Using analog computation capability of DRAM
 - Idea: activating multiple rows performs computation
- 30-60X performance and energy improvement
 - Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations Using Commodity DRAM Technology," MICRO 2017.

- New memory technologies enable even more opportunities
 - Memristors, resistive RAM, phase change mem, STT-MRAM, ...
 - Can operate on data with minimal movement

In-DRAM AND/OR: Triple Row Activation



Seshadri+, "Fast Bulk Bitwise AND and OR in DRAM", IEEE CAL 2015.

In-DRAM NOT: Dual Contact Cell



Figure 5: A dual-contact cell connected to both ends of a sense amplifier Idea: Feed the negated value in the sense amplifier into a special row

Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations using Commodity DRAM Technology," MICRO 2017.



Performance: In-DRAM Bitwise Operations



Figure 9: Throughput of bitwise operations on various systems.

Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations using Commodity DRAM Technology," MICRO 2017.
	Design	not	and/or	nand/nor	xor/xnor
DRAM &	DDR3	93.7	137.9	137.9	137.9
Channel Energy	Ambit	1.6	3.2	4.0	5.5
(nJ/KB)	(\downarrow)	59.5X	43.9X	35.1X	25.1X

Table 3: Energy of bitwise operations. (\downarrow) indicates energy reduction of Ambit over the traditional DDR3-based design.

Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations using Commodity DRAM Technology," MICRO 2017.

Ambit vs. DDR3: Performance and Energy

Performance Improvement

Energy Reduction



Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations using Commodity DRAM Technology," MICRO 2017.

Bulk Bitwise Operations in Workloads



SAFARI

[1] Li and Patel, BitWeaving, SIGMOD 2013[2] Goodwin+, BitFunnel, SIGIR 2017

Example Data Structure: Bitmap Index

- Alternative to B-tree and its variants
- Efficient for performing *range queries* and *joins*
- Many bitwise operations to perform a query



Performance: Bitmap Index on Ambit



Figure 10: Bitmap index performance. The value above each bar indicates the reduction in execution time due to Ambit.

Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations using Commodity DRAM Technology," MICRO 2017.

Performance: BitWeaving on Ambit

`select count(*) from T where c1 <= val <= c2`</pre>



Figure 11: Speedup offered by Ambit over baseline CPU with SIMD for BitWeaving

Seshadri+, "Ambit: In-Memory Accelerator for Bulk Bitwise Operations using Commodity DRAM Technology," MICRO 2017.

More on In-DRAM Bulk AND/OR

 Vivek Seshadri, Kevin Hsieh, Amirali Boroumand, Donghyuk Lee, Michael A. Kozuch, Onur Mutlu, Phillip B. Gibbons, and Todd C. Mowry,
<u>"Fast Bulk Bitwise AND and OR in DRAM"</u> <u>IEEE Computer Architecture Letters</u> (CAL), April 2015.

Fast Bulk Bitwise AND and OR in DRAM

Vivek Seshadri*, Kevin Hsieh*, Amirali Boroumand*, Donghyuk Lee*, Michael A. Kozuch[†], Onur Mutlu*, Phillip B. Gibbons[†], Todd C. Mowry* *Carnegie Mellon University [†]Intel Pittsburgh

More on Ambit

 Vivek Seshadri et al., "<u>Ambit: In-Memory Accelerator</u> for Bulk Bitwise Operations Using Commodity DRAM <u>Technology</u>," MICRO 2017.

Ambit: In-Memory Accelerator for Bulk Bitwise Operations Using Commodity DRAM Technology

Vivek Seshadri^{1,5} Donghyuk Lee^{2,5} Thomas Mullins^{3,5} Hasan Hassan⁴ Amirali Boroumand⁵ Jeremie Kim^{4,5} Michael A. Kozuch³ Onur Mutlu^{4,5} Phillip B. Gibbons⁵ Todd C. Mowry⁵

¹Microsoft Research India ²NVIDIA Research ³Intel ⁴ETH Zürich ⁵Carnegie Mellon University

Challenge and Opportunity for Future

Computing Architectures with

Minimal Data Movement



Challenge: Intelligent Memory Device

Does memory have to be dumb?



- Major Trends Affecting Main Memory
- The Need for Intelligent Memory Controllers
 - Bottom Up: Push from Circuits and Devices
 - Top Down: Pull from Systems and Applications
- Processing in Memory: Two Directions
 - Minimally Changing Memory Chips
 - Exploiting 3D-Stacked Memory
- How to Enable Adoption of Processing in Memory
- Conclusion

Processing in Memory: Two Approaches

Minimally changing memory chips
Exploiting 3D-stacked memory

Opportunity: 3D-Stacked Logic+Memory



Hybrid Memory Cube



DRAM Landscape (circa 2015)

Segment	DRAM Standards & Architectures
Commodity	DDR3 (2007) [14]; DDR4 (2012) [18]
Low-Power	LPDDR3 (2012) [17]; LPDDR4 (2014) [20]
Graphics	GDDR5 (2009) [15]
Performance	eDRAM [28], [32]; RLDRAM3 (2011) [29]
3D-Stacked	WIO (2011) [16]; WIO2 (2014) [21]; MCDRAM (2015) [13]; HBM (2013) [19]; HMC1.0 (2013) [10]; HMC1.1 (2014) [11]
Academic	SBA/SSA (2010) [38]; Staged Reads (2012) [8]; RAIDR (2012) [27]; SALP (2012) [24]; TL-DRAM (2013) [26]; RowClone (2013) [37]; Half-DRAM (2014) [39]; Row-Buffer Decoupling (2014) [33]; SARP (2014) [6]; AL-DRAM (2015) [25]

Table 1. Landscape of DRAM-based memory

Kim+, "Ramulator: A Flexible and Extensible DRAM Simulator", IEEE CAL 2015.

Two Key Questions in 3D-Stacked PIM

- How can we accelerate important applications if we use 3D-stacked memory as a coarse-grained accelerator?
 - what is the architecture and programming model?
 - what are the mechanisms for acceleration?

- What is the minimal processing-in-memory support we can provide?
 - without changing the system significantly
 - while achieving significant benefits

Graph Processing

Large graphs are everywhere (circa 2015)



Scalable large-scale graph processing is challenging



Key Bottlenecks in Graph Processing



Tesseract System for Graph Processing

Interconnected set of 3D-stacked memory+logic chips with simple cores



SAFARI Ahn+, "A Scalable Processing-in-Memory Accelerator for Parallel Graph Processing" ISCA 2015.

Tesseract System for Graph Processing



Tesseract System for Graph Processing



Communications In Tesseract (I)

```
for (v: graph.vertices) {
```

for (w: v.successors) {

w.next_rank += weight * v.rank;



Communications In Tesseract (II)

```
for (v: graph.vertices) {
```

for (w: v.successors) {

w.next_rank += weight * v.rank;



Communications In Tesseract (III)



Remote Function Call (Non-Blocking)

- 1. Send function address & args to the remote core
- 2. Store the incoming message to the message queue
- 3. Flush the message queue when it is full or a synchronization barrier is reached



put(w.id, function() { w.next_rank += value; })

Evaluated Systems



SAFARI Ahn+, "A Scalable Processing-in-Memory Accelerator for Parallel Graph Processing" ISCA 2015.

Tesseract Graph Processing Performance

>13X Performance Improvement



SAFARI Ahn+, "A Scalable Processing-in-Memory Accelerator for Parallel Graph Processing" ISCA 2015.

Tesseract Graph Processing Performance



Tesseract Graph Processing System Energy



SAFARI Ahn+, "A Scalable Processing-in-Memory Accelerator for Parallel Graph Processing" ISCA 2015.

More on Tesseract

 Junwhan Ahn, Sungpack Hong, Sungjoo Yoo, Onur Mutlu, and Kiyoung Choi,
"A Scalable Processing-in-Memory Accelerator for Parallel Graph Processing"
Proceedings of the <u>42nd International Symposium on</u> <u>Computer Architecture</u> (ISCA), Portland, OR, June 2015.
[Slides (pdf)] [Lightning Session Slides (pdf)]

A Scalable Processing-in-Memory Accelerator for Parallel Graph Processing

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PIM on Mobile Devices

 Amirali Boroumand, Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, and Onur Mutlu, "Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks"

Proceedings of the <u>23rd International Conference on Architectural</u> <u>Support for Programming Languages and Operating</u> <u>Systems</u> (**ASPLOS**), Williamsburg, VA, USA, March 2018.

Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand1Saugata Ghose1Youngsok Kim2Rachata Ausavarungnirun1Eric Shiu3Rahul Thakur3Daehyun Kim4,3Aki Kuusela3Allan Knies3Parthasarathy Ranganathan3Onur Mutlu^{5,1}

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Google

Consumer Devices



Consumer devices are everywhere!

Energy consumption is a first-class concern in consumer devices





Popular Google Consumer Workloads



Chrome

Google's web browser



TensorFlow Mobile

Google's machine learning framework



Google's video codec



Energy Cost of Data Movement

Ist key observation: 62.7% of the total system energy is spent on data movement



Processing-In-Memory (PIM)

Potential solution: move computation close to data

Challenge: limited area and energy budget

Using PIM to Reduce Data Movement

2nd key observation: a significant fraction of the data movement often comes from simple functions

We can design lightweight logic to implement these <u>simple functions</u> in <u>memory</u>

Small embedded low-power core

> PIM Core

Small fixed-function accelerators



Offloading to PIM logic reduces energy and improves performance, on average, by 55.4% and 54.2%

Workload Analysis





Google's web browser



TensorFlow Mobile

Google's machine learning framework



Google's video codec


TensorFlow Mobile



57.3% of the inference energy is spent on data movement

54.4% of the data movement energy comes from packing/unpacking and quantization



Packing



A simple data reorganization process that requires simple arithmetic

Quantization



A simple data conversion operation that requires shift, addition, and multiplication operations





inference execution time

A simple data conversion operation that requires shift, addition, and multiplication operations

Evaluation Methodology

- System Configuration (gem5 Simulator)
 - SoC: 4 OoO cores, 8-wide issue, 64 kB Ll cache, 2MB L2 cache
 - PIM Core: I core per vault, I-wide issue, 4-wide SIMD, 32kB LI cache
 - **3D-Stacked Memory: 2GB cube, 16 vaults per cube**
 - Internal Bandwidth: 256GB/S
 - Off-Chip Channel Bandwidth: 32 GB/s
 - Baseline Memory: LPDDR3, 2GB, FR-FCFS scheduler
- We study each target in isolation and emulate each separately and run them in our simulator 40 SAFARI

Normalized Energy

© CPU-Only ■ **PIM-Core** ■ **PIM-Acc**



77.7% and 82.6% of energy reduction for texture tiling and packing comes from eliminating data movement

PIM core and PIM accelerator reduces energy consumption on average by 49.1% and 55.4%

Normalized Runtime

Scpu-Only PIM-Core PIM-Acc



Offloading these kernels to PIM core and PIM accelerator improves performance on average by 44.6% and 54.2%

Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand

Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, Onur Mutlu

ASPLOS 2018

Carnegie Mellon







SEOUL NATIONAL UNIVERSITY



Google

More on PIM for Mobile Devices

 Amirali Boroumand, Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, and Onur Mutlu, "Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks" Proceedings of the <u>23rd International Conference on Architectural Support for Programming</u> <u>Languages and Operating Systems</u> (ASPLOS), Williamsburg, VA, USA, March 2018.

62.7% of the total system energy is spent on data movement

Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand¹Saugata Ghose¹Youngsok Kim²Rachata Ausavarungnirun¹Eric Shiu³Rahul Thakur³Daehyun Kim^{4,3}Aki Kuusela³Allan Knies³Parthasarathy Ranganathan³Onur Mutlu^{5,1}153

Truly Distributed GPU Processing with PIM?



Accelerating GPU Execution with PIM (I)

- Kevin Hsieh, Eiman Ebrahimi, Gwangsun Kim, Niladrish Chatterjee, Mike O'Connor, Nandita Vijaykumar, Onur Mutlu, and Stephen W. Keckler, <u>"Transparent Offloading and Mapping (TOM): Enabling</u> <u>Programmer-Transparent Near-Data Processing in GPU</u> <u>Systems"</u> *Proceedings of the <u>43rd International Symposium on Computer</u> <u>Architecture (ISCA)</u>, Seoul, South Korea, June 2016.*
 - [Slides (pptx) (pdf)]

[Lightning Session Slides (pptx) (pdf)]

Transparent Offloading and Mapping (TOM): Enabling Programmer-Transparent Near-Data Processing in GPU Systems

Kevin Hsieh[‡] Eiman Ebrahimi[†] Gwangsun Kim^{*} Niladrish Chatterjee[†] Mike O'Connor[†] Nandita Vijaykumar[‡] Onur Mutlu^{§‡} Stephen W. Keckler[†] [‡]Carnegie Mellon University [†]NVIDIA ^{*}KAIST [§]ETH Zürich

Accelerating GPU Execution with PIM (II)

 Ashutosh Pattnaik, Xulong Tang, Adwait Jog, Onur Kayiran, Asit K. Mishra, Mahmut T. Kandemir, <u>Onur Mutlu</u>, and Chita R. Das, <u>"Scheduling Techniques for GPU Architectures with Processing-</u> <u>In-Memory Capabilities"</u>

Proceedings of the <u>25th International Conference on Parallel</u> <u>Architectures and Compilation Techniques</u> (**PACT**), Haifa, Israel, September 2016.

Scheduling Techniques for GPU Architectures with Processing-In-Memory Capabilities

Ashutosh Pattnaik¹ Xulong Tang¹ Adwait Jog² Onur Kayıran³ Asit K. Mishra⁴ Mahmut T. Kandemir¹ Onur Mutlu^{5,6} Chita R. Das¹ ¹Pennsylvania State University ²College of William and Mary ³Advanced Micro Devices, Inc. ⁴Intel Labs ⁵ETH Zürich ⁶Carnegie Mellon University

Accelerating Linked Data Structures

 Kevin Hsieh, Samira Khan, Nandita Vijaykumar, Kevin K. Chang, Amirali Boroumand, Saugata Ghose, and Onur Mutlu, <u>"Accelerating Pointer Chasing in 3D-Stacked Memory:</u> <u>Challenges, Mechanisms, Evaluation"</u> *Proceedings of the <u>34th IEEE International Conference on Computer</u> <u>Design</u> (ICCD), Phoenix, AZ, USA, October 2016.*

Accelerating Pointer Chasing in 3D-Stacked Memory: Challenges, Mechanisms, Evaluation

Kevin Hsieh[†] Samira Khan[‡] Nandita Vijaykumar[†] Kevin K. Chang[†] Amirali Boroumand[†] Saugata Ghose[†] Onur Mutlu^{§†} [†]Carnegie Mellon University [‡]University of Virginia [§]ETH Zürich

Accelerating Dependent Cache Misses

 Milad Hashemi, Khubaib, Eiman Ebrahimi, Onur Mutlu, and Yale N. Patt, "Accelerating Dependent Cache Misses with an Enhanced <u>Memory Controller"</u> *Proceedings of the <u>43rd International Symposium on Computer</u> <i>Architecture (ISCA)*, Seoul, South Korea, June 2016. [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

Accelerating Dependent Cache Misses with an Enhanced Memory Controller

Milad Hashemi^{*}, Khubaib[†], Eiman Ebrahimi[‡], Onur Mutlu[§], Yale N. Patt^{*}

* The University of Texas at Austin [†]Apple [‡]NVIDIA [§]ETH Zürich & Carnegie Mellon University

Two Key Questions in 3D-Stacked PIM

- How can we accelerate important applications if we use 3D-stacked memory as a coarse-grained accelerator?
 - what is the architecture and programming model?
 - what are the mechanisms for acceleration?

What is the minimal processing-in-memory support we can provide?

- without changing the system significantly
- while achieving significant benefits

PEI: PIM-Enabled Instructions (Ideas)

- Goal: Develop mechanisms to get the most out of near-data processing with minimal cost, minimal changes to the system, no changes to the programming model
- Key Idea 1: Expose each PIM operation as a cache-coherent, virtually-addressed host processor instruction (called PEI) that operates on only a single cache block
 - e.g., __pim_add(&w.next_rank, value) \rightarrow pim.add r1, (r2)
 - No changes sequential execution/programming model
 - No changes to virtual memory
 - Minimal changes to cache coherence
 - No need for data mapping: Each PEI restricted to a single memory module
- Key Idea 2: Dynamically decide where to execute a PEI (i.e., the host processor or PIM accelerator) based on simple locality characteristics and simple hardware predictors
 - Execute each operation at the location that provides the best performance

Simple PIM Operations as ISA Extensions (II)

```
for (v: graph.vertices) {
  value = weight * v.rank;
  for (w: v.successors) {
    w.next rank += value;
      Host Processor
        w.next rank
                           64 bytes in
                          64 bytes out
```







Conventional Architecture

Simple PIM Operations as ISA Extensions (III)



In-Memory Addition



Executed either in memory or in the processor: dynamic decision

- Low-cost locality monitoring for a single instruction
- Cache-coherent, virtually-addressed, single cache block only
- Atomic between different PEIs
- Not atomic with normal instructions (use pfence for ordering)
 SAFARI

Example (Abstract) PEI uArchitecture



Example PEI uArchitecture

PEI: Initial Evaluation Results

Initial evaluations with 10 emerging data-intensive workloads

- Large-scale graph processing
- In-memory data analytics
- Machine learning and data mining
- Three input sets (small, medium, large) for each workload to analyze the impact of data locality

Table 2: Baseline Simulation Configuration

Component	Configuration
Core	16 out-of-order cores, 4 GHz, 4-issue
L1 I/D-Cache	Private, 32 KB, 4/8-way, 64 B blocks, 16 MSHRs
L2 Cache	Private, 256 KB, 8-way, 64 B blocks, 16 MSHRs
L3 Cache	Shared, 16 MB, 16-way, 64 B blocks, 64 MSHRs
On-Chip Network	Crossbar, 2 GHz, 144-bit links
Main Memory	32 GB, 8 HMCs, daisy-chain (80 GB/s full-duplex)
HMC	4 GB, 16 vaults, 256 DRAM banks [20]
– DRAM	FR-FCFS, tCL = tRCD = tRP = 13.75 ns [27]
 Vertical Links 	64 TSVs per vault with 2 Gb/s signaling rate [23]

Pin-based cycle-level x86-64 simulation

Performance Improvement and Energy Reduction:

- 47% average speedup with large input data sets
- 32% speedup with small input data sets
- 25% avg. energy reduction in a single node with large input data sets

Simpler PIM: PIM-Enabled Instructions

 Junwhan Ahn, Sungjoo Yoo, Onur Mutlu, and Kiyoung Choi, "PIM-Enabled Instructions: A Low-Overhead, Locality-Aware Processing-in-Memory Architecture" Proceedings of the <u>42nd International Symposium on</u> <u>Computer Architecture</u> (ISCA), Portland, OR, June 2015. [Slides (pdf)] [Lightning Session Slides (pdf)]

PIM-Enabled Instructions: A Low-Overhead, Locality-Aware Processing-in-Memory Architecture

Junwhan Ahn Sungjoo Yoo Onur Mutlu[†] Kiyoung Choi junwhan@snu.ac.kr, sungjoo.yoo@gmail.com, onur@cmu.edu, kchoi@snu.ac.kr Seoul National University [†]Carnegie Mellon University

Automatic Code and Data Mapping

- Kevin Hsieh, Eiman Ebrahimi, Gwangsun Kim, Niladrish Chatterjee, Mike O'Connor, Nandita Vijaykumar, Onur Mutlu, and Stephen W. Keckler, <u>"Transparent Offloading and Mapping (TOM): Enabling</u> <u>Programmer-Transparent Near-Data Processing in GPU</u> <u>Systems"</u> *Proceedings of the <u>43rd International Symposium on Computer</u> <u>Architecture</u> (ISCA), Seoul, South Korea, June 2016.*
 - [<u>Slides (pptx) (pdf)</u>]

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Transparent Offloading and Mapping (TOM): Enabling Programmer-Transparent Near-Data Processing in GPU Systems

Kevin Hsieh[‡] Eiman Ebrahimi[†] Gwangsun Kim^{*} Niladrish Chatterjee[†] Mike O'Connor[†] Nandita Vijaykumar[‡] Onur Mutlu^{§‡} Stephen W. Keckler[†] [‡]Carnegie Mellon University [†]NVIDIA ^{*}KAIST [§]ETH Zürich

Automatic Offloading of Critical Code

 Milad Hashemi, Khubaib, Eiman Ebrahimi, Onur Mutlu, and Yale N. Patt, "Accelerating Dependent Cache Misses with an Enhanced <u>Memory Controller"</u> *Proceedings of the <u>43rd International Symposium on Computer</u> <i>Architecture (ISCA)*, Seoul, South Korea, June 2016. [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

Accelerating Dependent Cache Misses with an Enhanced Memory Controller

Milad Hashemi^{*}, Khubaib[†], Eiman Ebrahimi[‡], Onur Mutlu[§], Yale N. Patt^{*}

* The University of Texas at Austin [†]Apple [‡]NVIDIA [§]ETH Zürich & Carnegie Mellon University

Automatic Offloading of Prefetch Mechanisms

 Milad Hashemi, Onur Mutlu, and Yale N. Patt,
 "Continuous Runahead: Transparent Hardware Acceleration for Memory Intensive Workloads"
 Proceedings of the <u>49th International Symposium on</u> <u>Microarchitecture</u> (MICRO), Taipei, Taiwan, October 2016.
 [Slides (pptx) (pdf)] [Lightning Session Slides (pdf)] [Poster (pptx) (pdf)]

Continuous Runahead: Transparent Hardware Acceleration for Memory Intensive Workloads

Milad Hashemi^{*}, Onur Mutlu[§], Yale N. Patt^{*}

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Efficient Automatic Data Coherence Support

 Amirali Boroumand, Saugata Ghose, Minesh Patel, Hasan Hassan, Brandon Lucia, Kevin Hsieh, Krishna T. Malladi, Hongzhong Zheng, and Onur Mutlu,
 "LazyPIM: An Efficient Cache Coherence Mechanism for Processing-in-Memory" IEEE Computer Architecture Letters (CAL), June 2016.

LazyPIM: An Efficient Cache Coherence Mechanism for Processing-in-Memory

Amirali Boroumand[†], Saugata Ghose[†], Minesh Patel[†], Hasan Hassan^{†§}, Brandon Lucia[†], Kevin Hsieh[†], Krishna T. Malladi^{*}, Hongzhong Zheng^{*}, and Onur Mutlu^{‡†} [†]Carnegie Mellon University *Samsung Semiconductor, Inc. § TOBB ETÜ [‡]ETH Zürich



Challenge and Opportunity for Future

Fundamentally **Energy-Efficient** (Data-Centric) **Computing Architectures** Challenge and Opportunity for Future

Fundamentally **High-Performance** (Data-Centric) **Computing Architectures** Challenge and Opportunity for Future

Computing Architectures with

Minimal Data Movement





- Major Trends Affecting Main Memory
- The Need for Intelligent Memory Controllers
 - Bottom Up: Push from Circuits and Devices
 - Top Down: Pull from Systems and Applications
- Processing in Memory: Two Directions
 - Minimally Changing Memory Chips
 - Exploiting 3D-Stacked Memory
- How to Enable Adoption of Processing in Memory
- Conclusion

Eliminating the Adoption Barriers

How to Enable Adoption of Processing in Memory

Barriers to Adoption of PIM

1. Functionality of and applications for PIM

2. Ease of programming (interfaces and compiler/HW support)

3. System support: coherence & virtual memory

4. Runtime systems for adaptive scheduling, data mapping, access/sharing control

5. Infrastructures to assess benefits and feasibility

We Need to Revisit the Entire Stack

Problem	
Aigorithm	
Program/Language	
System Software	
SW/HW Interface	
Micro-architecture	
Logic	
Devices	
Electrons	

Open Problems: PIM Adoption

Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions

SAUGATA GHOSE, KEVIN HSIEH, AMIRALI BOROUMAND, RACHATA AUSAVARUNGNIRUN

Carnegie Mellon University

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Saugata Ghose, Kevin Hsieh, Amirali Boroumand, Rachata Ausavarungnirun, Onur Mutlu, "Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions" Invited Book Chapter, to appear in 2018. [Preliminary arxiv.org version]

SAFARI

https://arxiv.org/pdf/1802.00320.pdf

Key Challenge 1: Code Mapping

• Challenge 1: Which operations should be executed in memory vs. in CPU?



Key Challenge 2: Data Mapping

• Challenge 2: How should data be mapped to different 3D memory stacks?


How to Do the Code and Data Mapping?

- Kevin Hsieh, Eiman Ebrahimi, Gwangsun Kim, Niladrish Chatterjee, Mike O'Connor, Nandita Vijaykumar, Onur Mutlu, and Stephen W. Keckler, <u>"Transparent Offloading and Mapping (TOM): Enabling</u> <u>Programmer-Transparent Near-Data Processing in GPU</u> <u>Systems"</u> *Proceedings of the <u>43rd International Symposium on Computer</u> <u>Architecture</u> (ISCA), Seoul, South Korea, June 2016.*
 - [<u>Slides (pptx) (pdf)</u>]

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Transparent Offloading and Mapping (TOM): Enabling Programmer-Transparent Near-Data Processing in GPU Systems

Kevin Hsieh[‡] Eiman Ebrahimi[†] Gwangsun Kim^{*} Niladrish Chatterjee[†] Mike O'Connor[†] Nandita Vijaykumar[‡] Onur Mutlu^{§‡} Stephen W. Keckler[†] [‡]Carnegie Mellon University [†]NVIDIA ^{*}KAIST [§]ETH Zürich

How to Schedule Code?

 Ashutosh Pattnaik, Xulong Tang, Adwait Jog, Onur Kayiran, Asit K. Mishra, Mahmut T. Kandemir, <u>Onur Mutlu</u>, and Chita R. Das, <u>"Scheduling Techniques for GPU Architectures with Processing-In-Memory Capabilities"
</u>

Proceedings of the <u>25th International Conference on Parallel</u> <u>Architectures and Compilation Techniques</u> (**PACT**), Haifa, Israel, September 2016.

Scheduling Techniques for GPU Architectures with Processing-In-Memory Capabilities

Ashutosh Pattnaik¹ Xulong Tang¹ Adwait Jog² Onur Kayıran³ Asit K. Mishra⁴ Mahmut T. Kandemir¹ Onur Mutlu^{5,6} Chita R. Das¹ ¹Pennsylvania State University ²College of William and Mary ³Advanced Micro Devices, Inc. ⁴Intel Labs ⁵ETH Zürich ⁶Carnegie Mellon University

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Challenge: Coherence for Hybrid CPU-PIM Apps



How to Maintain Coherence?

 Amirali Boroumand, Saugata Ghose, Minesh Patel, Hasan Hassan, Brandon Lucia, Kevin Hsieh, Krishna T. Malladi, Hongzhong Zheng, and Onur Mutlu,
 "LazyPIM: An Efficient Cache Coherence Mechanism for Processing-in-Memory" IEEE Computer Architecture Letters (CAL), June 2016.

LazyPIM: An Efficient Cache Coherence Mechanism for Processing-in-Memory

Amirali Boroumand[†], Saugata Ghose[†], Minesh Patel[†], Hasan Hassan^{†§}, Brandon Lucia[†], Kevin Hsieh[†], Krishna T. Malladi^{*}, Hongzhong Zheng^{*}, and Onur Mutlu^{‡†} [†]Carnegie Mellon University *Samsung Semiconductor, Inc. [§]TOBB ETÜ [‡]ETH Zürich



How to Support Virtual Memory?

 Kevin Hsieh, Samira Khan, Nandita Vijaykumar, Kevin K. Chang, Amirali Boroumand, Saugata Ghose, and Onur Mutlu, <u>"Accelerating Pointer Chasing in 3D-Stacked Memory:</u> <u>Challenges, Mechanisms, Evaluation"</u> *Proceedings of the <u>34th IEEE International Conference on Computer</u> <u>Design</u> (ICCD), Phoenix, AZ, USA, October 2016.*

Accelerating Pointer Chasing in 3D-Stacked Memory: Challenges, Mechanisms, Evaluation

Kevin Hsieh[†] Samira Khan[‡] Nandita Vijaykumar[†] Kevin K. Chang[†] Amirali Boroumand[†] Saugata Ghose[†] Onur Mutlu^{§†} [†]Carnegie Mellon University [‡]University of Virginia [§]ETH Zürich

How to Design Data Structures for PIM?

 Zhiyu Liu, Irina Calciu, Maurice Herlihy, and Onur Mutlu, "Concurrent Data Structures for Near-Memory Computing" Proceedings of the <u>29th ACM Symposium on Parallelism in Algorithms</u> <u>and Architectures</u> (SPAA), Washington, DC, USA, July 2017. [Slides (pptx) (pdf)]

Concurrent Data Structures for Near-Memory Computing

Zhiyu Liu Computer Science Department Brown University zhiyu_liu@brown.edu

Maurice Herlihy Computer Science Department Brown University mph@cs.brown.edu Irina Calciu VMware Research Group icalciu@vmware.com

Onur Mutlu Computer Science Department ETH Zürich onur.mutlu@inf.ethz.ch

Simulation Infrastructures for PIM

- Ramulator extended for PIM
 - Flexible and extensible DRAM simulator
 - Can model many different memory standards and proposals
 - Kim+, "Ramulator: A Flexible and Extensible DRAM Simulator", IEEE CAL 2015.
 - <u>https://github.com/CMU-SAFARI/ramulator</u>

Ramulator: A Fast and Extensible DRAM Simulator

Yoongu Kim¹ Weikun Yang^{1,2} Onur Mutlu¹ ¹Carnegie Mellon University ²Peking University

An FPGA-based Test-bed for PIM?

 Hasan Hassan et al., <u>SoftMC: A</u> <u>Flexible and Practical Open-</u> <u>Source Infrastructure for</u> <u>Enabling Experimental DRAM</u> <u>Studies</u> HPCA 2017.

- Flexible
- Easy to Use (C++ API)
- Open-source

github.com/CMU-SAFARI/SoftMC



Simulation Infrastructures for PIM (in SSDs)

 Arash Tavakkol, Juan Gomez-Luna, Mohammad Sadrosadati, Saugata Ghose, and <u>Onur Mutlu</u>, "MQSim: A Framework for Enabling Realistic Studies of Modern Multi-Queue SSD Devices" Proceedings of the <u>16th USENIX Conference on File and Storage</u> <u>Technologies</u> (FAST), Oakland, CA, USA, February 2018. [Slides (pptx) (pdf)]
 [Source Code]

MQSim: A Framework for Enabling Realistic Studies of Modern Multi-Queue SSD Devices

Arash Tavakkol[†], Juan Gómez-Luna[†], Mohammad Sadrosadati[†], Saugata Ghose[‡], Onur Mutlu^{†‡} [†]*ETH Zürich* [‡]*Carnegie Mellon University*

New Applications and Use Cases for PIM

 Jeremie S. Kim, Damla Senol Cali, Hongyi Xin, Donghyuk Lee, Saugata Ghose, Mohammed Alser, Hasan Hassan, Oguz Ergin, Can Alkan, and Onur Mutlu,
 "GRIM-Filter: Fast Seed Location Filtering in DNA Read Mapping Using Processing-in-Memory Technologies"

BMC Genomics, 2018. *Proceedings of the <u>16th Asia Pacific Bioinformatics Conference</u> (APBC), Yokohama, Japan, January 2018. <u>arxiv.org Version (pdf)</u>*

GRIM-Filter: Fast seed location filtering in DNA read mapping using processing-in-memory technologies

Jeremie S. Kim^{1,6*}, Damla Senol Cali¹, Hongyi Xin², Donghyuk Lee³, Saugata Ghose¹, Mohammed Alser⁴, Hasan Hassan⁶, Oguz Ergin⁵, Can Alkan^{4*} and Onur Mutlu^{6,1*}

From The Sixteenth Asia Pacific Bioinformatics Conference 2018 Yokohama, Japan. 15-17 January 2018

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Genome Read In-Memory (GRIM) Filter:

Fast Seed Location Filtering in DNA Read Mapping using Processing-in-Memory Technologies

Jeremie Kim,

Damla Senol, Hongyi Xin, Donghyuk Lee, Saugata Ghose, Mohammed Alser, Hasan Hassan, Oguz Ergin, Can Alkan, and Onur Mutlu







TOBB UNIVERSITY OF ECONOMICS AND TECHNOLOGY



Executive Summary

- Genome Read Mapping is a very important problem and is the first step in many types of genomic analysis
 - □ Could lead to improved health care, medicine, quality of life
- Read mapping is an **approximate string matching** problem
 - □ Find the best fit of 100 character strings into a 3 billion character dictionary
 - Alignment is currently the best method for determining the similarity between two strings, but is very expensive
- We propose an in-memory processing algorithm GRIM-Filter for accelerating read mapping, by reducing the number of required alignments
- We implement GRIM-Filter using in-memory processing within 3Dstacked memory and show up to 3.7x speedup.

Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand

Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, Onur Mutlu











Google

Open Problems: PIM Adoption

Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions

SAUGATA GHOSE, KEVIN HSIEH, AMIRALI BOROUMAND, RACHATA AUSAVARUNGNIRUN

Carnegie Mellon University

ONUR MUTLU ETH Zürich and Carnegie Mellon University

Saugata Ghose, Kevin Hsieh, Amirali Boroumand, Rachata Ausavarungnirun, Onur Mutlu, "Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions" Invited Book Chapter, to appear in 2018. [Preliminary arxiv.org version]

Enabling the Paradigm Shift

Computer Architecture Today

- You can revolutionize the way computers are built, if you understand both the hardware and the software (and change each accordingly)
- You can invent new paradigms for computation, communication, and storage
- Recommended book: Thomas Kuhn, "The Structure of Scientific Revolutions" (1962)
 - Pre-paradigm science: no clear consensus in the field
 - Normal science: dominant theory used to explain/improve things (business as usual); exceptions considered anomalies
 - Revolutionary science: underlying assumptions re-examined

Computer Architecture Today

You can revolutionize the way computers are built, if you oftware (and understand bot change each ac amazonicindia

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 - Pre-para THO
 - Normal things (I
 - Revoluti

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eld improve anomalies examined



- Major Trends Affecting Main Memory
- The Need for Intelligent Memory Controllers
 - Bottom Up: Push from Circuits and Devices
 - Top Down: Pull from Systems and Applications
- Processing in Memory: Two Directions
 - Minimally Changing Memory Chips
 - Exploiting 3D-Stacked Memory
- How to Enable Adoption of Processing in Memory
- Conclusion

Four Key Directions

Fundamentally Secure/Reliable/Safe Architectures

Fundamentally Energy-Efficient Architectures
 Memory-centric (Data-centric) Architectures

Fundamentally Low-Latency Architectures

Architectures for Genomics, Medicine, Health

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Maslow's Hierarchy of Needs, A Third Time



SAFARI Source: https://www.simplypsychology.org/maslow.html

Challenge and Opportunity for Future

Fundamentally **Energy-Efficient** (Data-Centric) **Computing Architectures**

Challenge and Opportunity for Future

Fundamentally Low-Latency (Data-Centric) **Computing Architectures**

Challenge and Opportunity for Future

Computing Architectures with

Minimal Data Movement



One Important Takeaway

Main Memory Needs Intelligent Controllers

Concluding Remarks

A Quote from A Famous Architect

 "architecture [...] based upon principle, and not upon precedent"



Precedent-Based Design?

"architecture [...] based upon principle, and not upon precedent"



Principled Design

"architecture [...] based upon principle, and not upon precedent"





The Overarching Principle

Organic architecture

From Wikipedia, the free encyclopedia

Organic architecture is a philosophy of architecture which promotes harmony between human habitation and the natural world through design approaches so sympathetic and well integrated with its site, that buildings, furnishings, and surroundings become part of a unified, interrelated composition.

A well-known example of organic architecture is Fallingwater, the residence Frank Lloyd Wright designed for the Kaufmann family in rural Pennsylvania. Wright had many choices to locate a home on this large site, but chose to place the home directly over the waterfall and creek creating a close, yet noisy dialog with the rushing water and the steep site. The horizontal striations of stone masonry with daring cantilevers of colored beige concrete blend with native rock outcroppings and the wooded environment.

Another Example: Precedent-Based Design



Principled Design



Another Principled Design



Source: By Martín Gómez Tagle - Lisbon, Portugal, CC BY-SA 3.0, https://commons.wikimedia.org/w/index.php?curid=13764903 Source: http://www.arcspace.com/exhibitions/unsorted/santiago-calatrava/

Another Principled Design



Principle Applied to Another Structure



The Overarching Principle

Zoomorphic architecture

From Wikipedia, the free encyclopedia

Zoomorphic architecture is the practice of using animal forms as the inspirational basis and blueprint for architectural design. "While animal forms have always played a role adding some of the deepest layers of meaning in architecture, it is now becoming evident that a new strand of biomorphism is emerging where the meaning derives not from any specific representation but from a more general allusion to biological processes."^[1]

Some well-known examples of Zoomorphic architecture can be found in the TWA Flight Center building in New York City, by Eero Saarinen, or the Milwaukee Art Museum by Santiago Calatrava, both inspired by the form of a bird's wings.^[3]
Overarching Principle for Computing?



Source: http://spectrum.ieee.org/image/MjYzMzAyMg.jpeg

Concluding Remarks

- It is time to design principled system architectures to solve the memory problem
- Design complete systems to be balanced, high-performance, and energy-efficient, i.e., data-centric (or memory-centric)
- Enable computation capability inside and close to memory
- This can
 - Lead to orders-of-magnitude improvements
 - Enable new applications & computing platforms
 - **Enable better understanding of nature**

The Future of Processing in Memory is Bright

- Regardless of challenges
 - in underlying technology and overlying problems/requirements

Can enable:

- Orders of magnitude improvements

- New applications and computing systems

	Problem					
	Aigorithm					
	Program/Language					
	System Software					
	SW/HW Interface					
	Micro-architecture					
	Logic					
	Devices					
	Electrons					

Yet, we have to

- Think across the stack
- Design enabling systems

If In Doubt, See Other Doubtful Technologies

- A very "doubtful" emerging technology
 - for at least two decades



Proceedings of the IEEE, Sept. 2017

Error Characterization, Mitigation, and Recovery in Flash-Memory-Based Solid-State Drives

This paper reviews the most recent advances in solid-state drive (SSD) error characterization, mitigation, and data recovery techniques to improve both SSD's reliability and lifetime.

By Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu

https://arxiv.org/pdf/1706.08642

For Some Open Problems, See

Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions

SAUGATA GHOSE, KEVIN HSIEH, AMIRALI BOROUMAND, RACHATA AUSAVARUNGNIRUN

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Saugata Ghose, Kevin Hsieh, Amirali Boroumand, Rachata Ausavarungnirun, Onur Mutlu, "Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions" Invited Book Chapter, to appear in 2018. [Preliminary arxiv.org version]

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https://arxiv.org/pdf/1802.00320.pdf

Accelerated Memory Course (~6.5 hours)

ACACES 2018

- Memory Systems and Memory-Centric Computing Systems
- Taught by Onur Mutlu July 9-13, 2018
- □ ~6.5 hours of lectures
- Website for the Course including Videos, Slides, Papers
 - https://people.inf.ethz.ch/omutlu/acaces2018.html
 - https://www.youtube.com/playlist?list=PL5Q2soXY2Zi-HXxomthrpDpMJm05P6J9x
- All Papers are at:
 - https://people.inf.ethz.ch/omutlu/projects.htm
 - Final lecture notes and readings (for all topics)

Processing Data Where It Makes Sense in Modern Computing Systems: Enabling In-Memory Computation

Onur Mutlu omutlu@gmail.com

https://people.inf.ethz.ch/omutlu

4 October 2018 HNEP 2018 Keynote

Systems @ ETH zürich





Slides Not Covered But Could Be Useful

Readings, Videos, Reference Materials

Accelerated Memory Course (~6.5 hours)

ACACES 2018

- Memory Systems and Memory-Centric Computing Systems
- Taught by Onur Mutlu July 9-13, 2018
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- All Papers are at:
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 - Final lecture notes and readings (for all topics)

Reference Overview Paper I

Enabling the Adoption of Processing-in-Memory: Challenges, Mechanisms, Future Research Directions

SAUGATA GHOSE, KEVIN HSIEH, AMIRALI BOROUMAND, RACHATA AUSAVARUNGNIRUN

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ONUR MUTLU ETH Zürich and Carnegie Mellon University

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SAFARI

https://arxiv.org/pdf/1802.00320.pdf

Reference Overview Paper II

 Onur Mutlu and Lavanya Subramanian, <u>"Research Problems and Opportunities in Memory</u> <u>Systems"</u> *Invited Article in <u>Supercomputing Frontiers and Innovations</u> (SUPERFRI), 2014/2015.*

Research Problems and Opportunities in Memory Systems

Onur Mutlu¹, Lavanya Subramanian¹

https://people.inf.ethz.ch/omutlu/pub/memory-systems-research_superfri14.pdf

Reference Overview Paper III

Onur Mutlu, "The RowHammer Problem and Other Issues We May Face as Memory Becomes Denser" Invited Paper in Proceedings of the Design, Automation, and Test in Europe Conference (DATE), Lausanne, Switzerland, March 2017. [Slides (pptx) (pdf)]

The RowHammer Problem and Other Issues We May Face as Memory Becomes Denser

Onur Mutlu ETH Zürich onur.mutlu@inf.ethz.ch https://people.inf.ethz.ch/omutlu

https://people.inf.ethz.ch/omutlu/pub/rowhammer-and-other-memory-issues_date17.pdf

Reference Overview Paper IV

Onur Mutlu,
 <u>"Memory Scaling: A Systems Architecture</u>
 <u>Perspective"</u>
 Technical talk at <u>MemCon 2013</u> (MEMCON), Santa Clara,
 CA, August 2013. [Slides (pptx) (pdf)]
 [Video] [Coverage on StorageSearch]

Memory Scaling: A Systems Architecture Perspective

Onur Mutlu Carnegie Mellon University onur@cmu.edu http://users.ece.cmu.edu/~omutlu/

https://people.inf.ethz.ch/omutlu/pub/memory-scaling_memcon13.pdf

Reference Overview Paper V



Proceedings of the IEEE, Sept. 2017

Error Characterization, Mitigation, and Recovery in Flash-Memory-Based Solid-State Drives

This paper reviews the most recent advances in solid-state drive (SSD) error characterization, mitigation, and data recovery techniques to improve both SSD's reliability and lifetime.

By YU CAI, SAUGATA GHOSE, ERICH F. HARATSCH, YIXIN LUO, AND ONUR MUTLU

https://arxiv.org/pdf/1706.08642

Related Videos and Course Materials (I)

- <u>Undergraduate Computer Architecture Course Lecture</u> <u>Videos (2015, 2014, 2013)</u>
- <u>Undergraduate Computer Architecture Course</u> <u>Materials</u> (2015, 2014, 2013)
- Graduate Computer Architecture Course Lecture Videos (2017, 2015, 2013)
- Graduate Computer Architecture Course Materials (2017, 2015, 2013)
- Parallel Computer Architecture Course Materials (Lecture Videos)

Related Videos and Course Materials (II)

- Freshman Digital Circuits and Computer Architecture Course Lecture Videos (2018, 2017)
- Freshman Digital Circuits and Computer Architecture Course Materials (2018)
- <u>Memory Systems Short Course Materials</u> (<u>Lecture Video on Main Memory and DRAM Basics</u>)

Some Open Source Tools (I)

- Rowhammer Program to Induce RowHammer Errors
 - https://github.com/CMU-SAFARI/rowhammer
- Ramulator Fast and Extensible DRAM Simulator
 - https://github.com/CMU-SAFARI/ramulator
- MemSim Simple Memory Simulator
 - https://github.com/CMU-SAFARI/memsim
- NOCulator Flexible Network-on-Chip Simulator
 - https://github.com/CMU-SAFARI/NOCulator
- SoftMC FPGA-Based DRAM Testing Infrastructure
 - https://github.com/CMU-SAFARI/SoftMC
- Other open-source software from my group
 - https://github.com/CMU-SAFARI/

<u>http://www.ece.cmu.edu/~safari/tools.html</u>
SAFARI

Some Open Source Tools (II)

- MQSim A Fast Modern SSD Simulator
 - https://github.com/CMU-SAFARI/MQSim
- Mosaic GPU Simulator Supporting Concurrent Applications
 - https://github.com/CMU-SAFARI/Mosaic
- IMPICA Processing in 3D-Stacked Memory Simulator
 - https://github.com/CMU-SAFARI/IMPICA
- SMLA Detailed 3D-Stacked Memory Simulator
 - https://github.com/CMU-SAFARI/SMLA
- HWASim Simulator for Heterogeneous CPU-HWA Systems
 <u>https://github.com/CMU-SAFARI/HWASim</u>
- Other open-source software from my group
 - https://github.com/CMU-SAFARI/

<u>http://www.ece.cmu.edu/~safari/tools.html</u>
SAFARI

More Open Source Tools (III)

- A lot more open-source software from my group
 - https://github.com/CMU-SAFARI/
 - http://www.ece.cmu.edu/~safari/tools.html

SAFARI Research Group at ETH Zurich and Carnegie Mellon University							
Site for so © ETH Zu Repositories 30	Durce code and tools distribution and Carnegi 🕑 http://www.second.com/action/second-tools	ution from SAFARI Res //www.ece.cmu.ed	earch Group at ETH Zurich ⊠ omutlu@gmail.com) ☆ Settings	n and Carnegie Mellon University.			
Search repositories		Type: All -	Language: All 🗸	Customize pinned repositories			
MQSim MQSim is a fast and accurat modern multi-queue (MQ) S MQSim faithfully models new steady-state SSD conditions	e simulator modeling the pe SDs as well as traditional SA w high-bandwidth protocol i s, and the full end-to-end la	erformance of ATA based SSDs. Implementations, tency of	M^	Top languages ● C++ ● C ● C# ● AGS Script ● Verilog			
requests in modern SSDs. It paper by A ● C++ ★ 14	is described in detail in the /IT Updated 8 days ago	FAST 2018		Most used topics Manage dram reliability			



All are available at

https://people.inf.ethz.ch/omutlu/projects.htm

http://scholar.google.com/citations?user=7XyGUGkAAAAJ&hl=en

https://people.inf.ethz.ch/omutlu/acaces2018.html



Ramulator: A Fast and Extensible DRAM Simulator [IEEE Comp Arch Letters'15]

Ramulator Motivation

- DRAM and Memory Controller landscape is changing
- Many new and upcoming standards
- Many new controller designs
- A fast and easy-to-extend simulator is very much needed

Segment	DRAM Standards & Architectures				
Commodity	DDR3 (2007) [14]; DDR4 (2012) [18]				
Low-Power	LPDDR3 (2012) [17]; LPDDR4 (2014) [20]				
Graphics	GDDR5 (2009) [15]				
Performance	eDRAM [28], [32]; RLDRAM3 (2011) [29]				
3D-Stacked	WIO (2011) [16]; WIO2 (2014) [21]; MCDRAM (2015) [13]; HBM (2013) [19]; HMC1.0 (2013) [10]; HMC1.1 (2014) [11]				
Academic	SBA/SSA (2010) [38]; Staged Reads (2012) [8]; RAIDR (2012) [27]; SALP (2012) [24]; TL-DRAM (2013) [26]; RowClone (2013) [37]; Half-DRAM (2014) [39]; Row-Buffer Decoupling (2014) [33]; SARP (2014) [6]; AL-DRAM (2015) [25]				
	Table 1. Landscape of DRAM-based memory				

Ramulator

- Provides out-of-the box support for many DRAM standards:
 - DDR3/4, LPDDR3/4, GDDR5, WIO1/2, HBM, plus new proposals (SALP, AL-DRAM, TLDRAM, RowClone, and SARP)
- ~2.5X faster than fastest open-source simulator
- Modular and extensible to different standards

Simulator	Cycles (10 ⁶)		Runtime (sec.)		<i>Req/sec</i> (10 ³)		Memory	
(clang -03)	Random	Stream	Random	Stream	Random	Stream	(<i>MB</i>)	
Ramulator	652	411	752	249	133	402	2.1	
DRAMSim2	645	413	2,030	876	49	114	1.2	
USIMM	661	409	1,880	750	53	133	4.5	
DrSim	647	406	18,109	12,984	6	8	1.6	
NVMain	666	413	6,881	5,023	15	20	4,230.0	

Table 3. Comparison of five simulators using two traces

Case Study: Comparison of DRAM Standards

Standard	Rate (MT/s)	Timing (CL-RCD-RP)	Data-Bus (Width×Chan.)	Rank-per-Chan	BW (GB/s)
DDR3	1,600	11-11-11	64 -bit $\times 1$	1	11.9
DDR4	2,400	16-16-16	64 -bit $\times 1$	1	17.9
SALP [†]	1,600	11-11-11	64 -bit $\times 1$	1	11.9
LPDDR3	1,600	12 - 15 - 15	64 -bit $\times 1$	1	11.9
LPDDR4	2,400	22-22-22	32 -bit $ imes 2^*$	1	17.9
GDDR5 [1	2] 6,000	18-18-18	64 -bit $\times 1$	1	44.7
HBM	1,000	7-7-7	128 -bit $\times 8^*$	1	119.2
WIO	266	7-7-7	128 -bit $\times 4^*$	1	15.9
WIO2	1,066	9-10-10	128 -bit $ imes 8^*$	1	127.2



Ramulator Paper and Source Code

- Yoongu Kim, Weikun Yang, and Onur Mutlu,
 "Ramulator: A Fast and Extensible DRAM Simulator"
 <u>IEEE Computer Architecture Letters</u> (CAL), March 2015.
 [Source Code]
- Source code is released under the liberal MIT License
 <u>https://github.com/CMU-SAFARI/ramulator</u>

Ramulator: A Fast and Extensible DRAM Simulator

Yoongu Kim¹ Weikun Yang^{1,2} Onur Mutlu¹ ¹Carnegie Mellon University ²Peking University

Tesseract: Extra Slides

Communications In Tesseract (I)

```
for (v: graph.vertices) {
```

for (w: v.successors) {

w.next_rank += weight * v.rank;



Communications In Tesseract (II)

```
for (v: graph.vertices) {
```

for (w: v.successors) {

w.next_rank += weight * v.rank;



Communications In Tesseract (III)



Remote Function Call (Non-Blocking)

- 1. Send function address & args to the remote core
- 2. Store the incoming message to the message queue
- 3. Flush the message queue when it is full or a synchronization barrier is reached



put(w.id, function() { w.next_rank += value; })

Effect of Bandwidth & Programming Model



Reducing Memory Latency

Main Memory Latency Lags Behind



Memory latency remains almost constant

A Closer Look ...



Figure 1: DRAM latency trends over time [20, 21, 23, 51].

Chang+, "<u>Understanding Latency Variation in Modern DRAM Chips: Experimental</u> Characterization, Analysis, and Optimization"," SIGMETRICS 2016.

DRAM Latency Is Critical for Performance



In-memory Databases

[Mao+, EuroSys'12; Clapp+ (**Intel**), IISWC'15]



In-Memory Data Analytics

[Clapp+ (**Intel**), IISWC'15; Awan+, BDCloud'15]



Graph/Tree Processing [Xu+, IISWC'12; Umuroglu+, FPL'15]



Datacenter Workloads [Kanev+ (**Google**), ISCA'15]
DRAM Latency Is Critical for Performance





In-memory Databases

Graph/Tree Processing

Long memory latency → performance bottleneck



In-Memory Data Analytics

[Clapp+ (**Intel**), IISWC'15; Awan+, BDCloud'15]



Datacenter Workloads

[Kanev+ (Google), ISCA'I5]

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Design of DRAM uArchitecture

• Goal: Maximize capacity/area, not minimize latency

"One size fits all" approach to latency specification

- Same latency parameters for all temperatures
- Same latency parameters for all DRAM chips (e.g., rows)
- Same latency parameters for all parts of a DRAM chip
- Same latency parameters for all supply voltage levels
- Same latency parameters for all application data

• ...

Latency Variation in Memory Chips

Heterogeneous manufacturing & operating conditions → latency variation in timing parameters



DRAM Characterization Infrastructure



SAFARI

Kim+, "Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors," ISCA 2014.

256

DRAM Characterization Infrastructure

 Hasan Hassan et al., <u>SoftMC: A</u> <u>Flexible and Practical Open-</u> <u>Source Infrastructure for</u> <u>Enabling Experimental DRAM</u> <u>Studies</u>, HPCA 2017.

- Flexible
- Easy to Use (C++ API)
- Open-source

github.com/CMU-SAFARI/SoftMC



SoftMC: Open Source DRAM Infrastructure

<u>https://github.com/CMU-SAFARI/SoftMC</u>

SoftMC: A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies

Hasan Hassan^{1,2,3} Nandita Vijaykumar³ Samira Khan^{4,3} Saugata Ghose³ Kevin Chang³ Gennady Pekhimenko^{5,3} Donghyuk Lee^{6,3} Oguz Ergin² Onur Mutlu^{1,3}

¹ETH Zürich ²TOBB University of Economics & Technology ³Carnegie Mellon University ⁴University of Virginia ⁵Microsoft Research ⁶NVIDIA Research

Tackling the Fixed Latency Mindset

- Reliable operation latency is actually very heterogeneous
 Across temperatures, chips, parts of a chip, voltage levels, ...
- Idea: Dynamically find out and use the lowest latency one can reliably access a memory location with
 - Adaptive-Latency DRAM [HPCA 2015]
 - Flexible-Latency DRAM [SIGMETRICS 2016]
 - Design-Induced Variation-Aware DRAM [SIGMETRICS 2017]
 - Voltron [SIGMETRICS 2017]
 - ••••
- We would like to find sources of latency heterogeneity and exploit them to minimize latency

Adaptive-Latency DRAM

- Key idea
 - Optimize DRAM timing parameters online
- Two components
 - DRAM manufacturer provides multiple sets of reliable DRAM timing parameters at different temperatures for each DIMM
 - System monitors DRAM temperature & uses appropriate DRAM timing parameters

SAFARI Lee+, "Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common-Case," HPCA 260 2015.

Latency Reduction Summary of 115 DIMMs

- Latency reduction for read & write (55°C)
 - Read Latency: **32.7%**
 - Write Latency: 55.1%
- Latency reduction for each timing parameter (55°C)
 - Sensing: **17.3%**
 - Restore: 37.3% (read), 54.8% (write)
 - Precharge: **35.2%**

SAFARI Lee+, "Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common-Case," HPCA 261 2015.

AL-DRAM: Real System Evaluation

System

- CPU: AMD 4386 (8 Cores, 3.1GHz, 8MB LLC)

D18F2	x200_dct[0]_1	mp[1:0] DDR3 DRAM Timing 0
Reset: 0)F05_0505h. S	See 2.9.3 [DCT Configuration Registers].
Bits	Description	
31:30	Reserved.	
29:24	Tras: row active strobe . Read-write. BIOS: See 2.9.7.5 [SPD ROM-Based Configuration]. Specifies the minimum time in memory clock cycles from an activate command to a precharge command, both to the same chip select bank.	
	<u>Bits</u> 07h-00h 2Ah-08h 3Fh-2Bh	Description Reserved <tras> clocks Reserved</tras>
23:21	Reserved.	
	1	

Trp: row precharge time. Read-write. BIOS: See 2.9.7.5 [SPD ROM-Based Configuration]. Speci-20:16fies the minimum time in memory clock cycles from a precharge command to an activate command or auto refresh command, both to the same bank.



AL-DRAM *improves single-core performance* on a real system

AL-DRAM: Multi-Core Evaluation



AL-DRAM provides higher performance on multi-programmed & multi-threaded workloads SAFARI

Reducing Latency Also Reduces Energy

- AL-DRAM reduces DRAM power consumption by 5.8%
- Major reason: reduction in row activation time

More on Adaptive-Latency DRAM

 Donghyuk Lee, Yoongu Kim, Gennady Pekhimenko, Samira Khan, Vivek Seshadri, Kevin Chang, and Onur Mutlu,
 <u>"Adaptive-Latency DRAM: Optimizing DRAM Timing for</u> <u>the Common-Case"</u>
 Proceedings of the <u>21st International Symposium on High-</u> <i>Performance Computer Architecture (HPCA), Bay Area, CA, February 2015.
 [Slides (pptx) (pdf)] [Full data sets]

Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common-Case

Donghyuk Lee Yoongu Kim Gennady Pekhimenko Samira Khan Vivek Seshadri Kevin Chang Onur Mutlu

Carnegie Mellon University

Heterogeneous Latency within A Chip



40 Workloads

Chang+, "<u>Understanding Latency Variation in Modern DRAM Chips: Experimental</u> Characterization, Analysis, and Optimization"," SIGMETRICS 2016.

SAFARI

Analysis of Latency Variation in DRAM Chips

- Kevin Chang, Abhijith Kashyap, Hasan Hassan, Samira Khan, Kevin Hsieh, Donghyuk Lee, Saugata Ghose, Gennady Pekhimenko, Tianshi Li, and Onur Mutlu,
 - "Understanding Latency Variation in Modern DRAM Chips: Experimental Characterization, Analysis, and Optimization"
 - Proceedings of the <u>ACM International Conference on Measurement and</u> <u>Modeling of Computer Systems</u> (**SIGMETRICS**), Antibes Juan-Les-Pins, France, June 2016. [Slides (pptx) (pdf)]

[Source Code]

Understanding Latency Variation in Modern DRAM Chips: Experimental Characterization, Analysis, and Optimization

Kevin K. Chang¹ Abhijith Kashyap¹ Hasan Hassan^{1,2} Saugata Ghose¹ Kevin Hsieh¹ Donghyuk Lee¹ Tianshi Li^{1,3} Gennady Pekhimenko¹ Samira Khan⁴ Onur Mutlu^{5,1} ¹Carnegie Mellon University ²TOBB ETÜ ³Peking University ⁴University of Virginia ⁵ETH Zürich SAFARI



Systematic variation in cell access times caused by the *physical organization* of DRAM

SAFARI



Profile only slow regions to determine min. latency → Dynamic & low cost latency optimization



Combine error-correcting codes & online profiling → Reliably reduce DRAM latency

DIVA-DRAM Reduces Latency



DIVA-DRAM *reduces latency more aggressively* and uses ECC to correct random slow cells

SAFARI

Design-Induced Latency Variation in DRAM

- Donghyuk Lee, Samira Khan, Lavanya Subramanian, Saugata Ghose, Rachata Ausavarungnirun, Gennady Pekhimenko, Vivek Seshadri, and <u>Onur Mutlu</u>,
 - "Design-Induced Latency Variation in Modern DRAM Chips: Characterization, Analysis, and Latency Reduction Mechanisms" Proceedings of the <u>ACM International Conference on Measurement and</u> <u>Modeling of Computer Systems</u> (SIGMETRICS), Urbana-Champaign, IL, USA, June 2017.

Design-Induced Latency Variation in Modern DRAM Chips: Characterization, Analysis, and Latency Reduction Mechanisms

Donghyuk Lee, NVIDIA and Carnegie Mellon University

Samira Khan, University of Virginia

Lavanya Subramanian, Saugata Ghose, Rachata Ausavarungnirun, Carnegie Mellon University

Gennady Pekhimenko, Vivek Seshadri, Microsoft Research

Onur Mutlu, ETH Zürich and Carnegie Mellon University

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Voltron: Exploiting the Voltage-Latency-Reliability Relationship

Executive Summary

- DRAM (memory) power is significant in today's systems
 - Existing low-voltage DRAM reduces voltage **conservatively**
- <u>Goal</u>: Understand and exploit the reliability and latency behavior of real DRAM chips under *aggressive reduced-voltage operation*
- Key experimental observations:
 - Huge voltage margin -- Errors occur beyond some voltage
 - Errors exhibit spatial locality
 - Higher operation latency mitigates voltage-induced errors
- <u>Voltron</u>: A new DRAM energy reduction mechanism
 - Reduce DRAM voltage without introducing errors
 - Use a **regression model** to select voltage that does not degrade performance beyond a chosen target \rightarrow 7.3% system energy reduction

SAFARI

Analysis of Latency-Voltage in DRAM Chips

 Kevin Chang, A. Giray Yaglikci, Saugata Ghose, Aditya Agrawal, Niladrish Chatterjee, Abhijith Kashyap, Donghyuk Lee, Mike O'Connor, Hasan Hassan, and <u>Onur Mutlu</u>, <u>"Understanding Reduced-Voltage Operation in Modern DRAM</u> <u>Devices: Experimental Characterization, Analysis, and</u> <u>Mechanisms"</u> *Proceedings of the <u>ACM International Conference on Measurement and</u> <u>Modeling of Computer Systems</u> (<i>SIGMETRICS*), Urbana-Champaign, IL, USA, June 2017.

Understanding Reduced-Voltage Operation in Modern DRAM Chips: Characterization, Analysis, and Mechanisms

Kevin K. Chang[†] Abdullah Giray Yağlıkçı[†] Saugata Ghose[†] Aditya Agrawal[¶] Niladrish Chatterjee[¶] Abhijith Kashyap[†] Donghyuk Lee[¶] Mike O'Connor^{¶,‡} Hasan Hassan[§] Onur Mutlu^{§,†}

[†]Carnegie Mellon University [¶]NVIDIA [‡]The University of Texas at Austin [§]ETH Zürich

And, What If ...

we can sacrifice reliability of some data to access it with even lower latency? The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

<u>Jeremie S. Kim</u> Minesh Patel Hasan Hassan Onur Mutlu









Motivation

• A **PUF** is function that generates a signature **unique** to a given device

- Used in a Challenge-Response Protocol
 - Each device generates a unique **PUF response** depending the inputs
 - A trusted server **authenticates** a device if it generates the expected PUF response

DRAM Latency Characterization of 223 LPDDR4 DRAM Devices

• Latency failures come from accessing DRAM with **reduced** timing parameters.

- Key Observations:
 - 1. A cell's **latency failure** probability is determined by **random process variation**
 - 2. Latency failure patterns are **repeatable and unique to a device**

DRAM Latency PUF Key Idea



DRAM Accesses and Failures



DRAM Accesses and Failures



The DRAM Latency PUF Evaluation

• We generate PUF responses using **latency errors** in a region of DRAM

The latency error patterns satisfy PUF requirements

• The DRAM Latency PUF generates PUF responses in 88.2ms

Results



• We are **orders of magnitude faster** than prior DRAM PUFs! SAFARI

The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

Jeremie S. Kim Minesh Patel

Hasan Hassan Onur Mutlu





QR Code for the paper

https://people.inf.ethz.ch/omutlu/pub/dram-latency-puf_hpca18.pd



Carnegie Mellon

HPCA 2018

SAFARI

DRAM Latency PUFs

 Jeremie S. Kim, Minesh Patel, Hasan Hassan, and <u>Onur Mutlu</u>, "The DRAM Latency PUF: Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern DRAM Devices"
 Dressedings of the 24th International Company on Uigh Derformance

Proceedings of the <u>24th International Symposium on High-Performance</u> <u>Computer Architecture</u> (**HPCA**), Vienna, Austria, February 2018. [Lightning Talk Video] [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

> Jeremie S. Kim^{†§} Minesh Patel[§] Hasan Hassan[§] Onur Mutlu^{§†} [†]Carnegie Mellon University [§]ETH Zürich

Tiered Latency DRAM
What Causes the Long Latency? **DRAM** Chip subarray Subarray 0 1/0 channel **1** DRAM Latency = Subarray Latency + II/O Latency Dominant

Why is the Subarray So Slow?



- Long bitline
 - Amortizes sense amplifier cost \rightarrow Small area



Trade-Off: Area (Die Size) vs. Latency



Approximating the Best of Both Worlds



Approximating the Best of Both Worlds



Commodity DRAM vs. TL-DRAM [HPCA 2013]

• DRAM Latency (tRC) • DRAM Power



DRAM Area Overhead

~3%: mainly due to the isolation transistors

Trade-Off: Area (Die-Area) vs. Latency



Leveraging Tiered-Latency DRAM

- TL-DRAM is a *substrate* that can be leveraged by the hardware and/or software
- Many potential uses

 Use near segment as hardware-managed *inclusive* cache to far segment

- 2. Use near segment as hardware-managed *exclusive* cache to far segment
- 3. Profile-based page mapping by operating system
- 4. Simply replace DRAM with TL-DRAM

Performance & Power Consumption



Using near segment as a cache improves performance and reduces power consumption

Lee+, "Tiered-Latency DRAM: A Low Latency and Low Cost DRAM Architecture," HPCA 2013.

Challenge and Opportunity for Future

Fundamentally Low Latency Computing Architectures



Ramulator: A Fast and Extensible DRAM Simulator [IEEE Comp Arch Letters'15]

Ramulator Motivation

- DRAM and Memory Controller landscape is changing
- Many new and upcoming standards
- Many new controller designs
- A fast and easy-to-extend simulator is very much needed

Segment	DRAM Standards & Architectures
Commodity	DDR3 (2007) [14]; DDR4 (2012) [18]
Low-Power	LPDDR3 (2012) [17]; LPDDR4 (2014) [20]
Graphics	GDDR5 (2009) [15]
Performance	eDRAM [28], [32]; RLDRAM3 (2011) [29]
3D-Stacked	WIO (2011) [16]; WIO2 (2014) [21]; MCDRAM (2015) [13]; HBM (2013) [19]; HMC1.0 (2013) [10]; HMC1.1 (2014) [11]
Academic	SBA/SSA (2010) [38]; Staged Reads (2012) [8]; RAIDR (2012) [27]; SALP (2012) [24]; TL-DRAM (2013) [26]; RowClone (2013) [37]; Half-DRAM (2014) [39]; Row-Buffer Decoupling (2014) [33]; SARP (2014) [6]; AL-DRAM (2015) [25]
	Table 1. Landscape of DRAM-based memory

Ramulator

- Provides out-of-the box support for many DRAM standards:
 - DDR3/4, LPDDR3/4, GDDR5, WIO1/2, HBM, plus new proposals (SALP, AL-DRAM, TLDRAM, RowClone, and SARP)
- ~2.5X faster than fastest open-source simulator
- Modular and extensible to different standards

Simulator	Cycles (10^6)		Runtime (sec.)		<i>Req/sec</i> (10 ³)		Memory	
(clang -03)	Random	Stream	Random	Stream	Random	Stream	(<i>MB</i>)	
Ramulator	652	411	752	249	133	402	2.1	
DRAMSim2	645	413	2,030	876	49	114	1.2	
USIMM	661	409	1,880	750	53	133	4.5	
DrSim	647	406	18,109	12,984	6	8	1.6	
NVMain	666	413	6,881	5,023	15	20	4,230.0	

Table 3. Comparison of five simulators using two traces

Case Study: Comparison of DRAM Standards

Standard	Rate (MT/s)	Timing (CL-RCD-RP)	Data-Bus (Width×Chan.)	Rank-per-Chan	BW (GB/s)
DDR3	1,600	11-11-11	64 -bit $\times 1$	1	11.9
DDR4	2,400	16-16-16	64 -bit $\times 1$	1	17.9
SALP [†]	1,600	11-11-11	64 -bit $\times 1$	1	11.9
LPDDR3	1,600	12 - 15 - 15	64 -bit $\times 1$	1	11.9
LPDDR4	2,400	22-22-22	32 -bit $ imes 2^*$	1	17.9
GDDR5 [1	2] 6,000	18-18-18	64 -bit $\times 1$	1	44.7
HBM	1,000	7-7-7	128 -bit $\times 8^*$	1	119.2
WIO	266	7-7-7	128 -bit $\times 4^*$	1	15.9
WIO2	1,066	9-10-10	128 -bit $ imes 8^*$	1	127.2



Ramulator Paper and Source Code

- Yoongu Kim, Weikun Yang, and <u>Onur Mutlu</u>,
 "Ramulator: A Fast and Extensible DRAM Simulator" <u>IEEE Computer Architecture Letters</u> (CAL), March 2015.
 [Source Code]
- Source code is released under the liberal MIT License
 <u>https://github.com/CMU-SAFARI/ramulator</u>

A Deeper Dive into DRAM Reliability Issues

There are Two Other Solution Directions

New Technologies: Replace or (more likely) augment DRAM with a different technology
 Non-volatile memories

Embracing Un-reliability:

Design memories with different reliability and store data intelligently across them

	Problem
	Aigorithm
	Program/Language
	System Software
	SW/HW Interface
	Micro-architecture
	Logic
	Devices
	Electrons

Fundamental solutions to security require co-design across the hierarchy

Exploiting Memory Error Tolerance with Hybrid Memory Systems



On Microsoft's Web Search workload Reduces server hardware cost by 4.7 % Achieves single server availability target of 99.90 % Heterogeneous-Reliability Memory [DSN 2014]

More on Heterogeneous-Reliability Memory

Yixin Luo, Sriram Govindan, Bikash Sharma, Mark Santaniello, Justin Meza, Aman Kansal, Jie Liu, Badriddine Khessib, Kushagra Vaid, and Onur Mutlu,
 <u>"Characterizing Application Memory Error Vulnerability to Optimize</u>
 <u>Data Center Cost via Heterogeneous-Reliability Memory"</u>
 *Proceedings of the <u>44th Annual IEEE/IFIP International Conference on</u>
 <u>Dependable Systems and Networks</u> (DSN), Atlanta, GA, June 2014. [Summary]
 [Slides (pptx) (pdf)] [Coverage on ZDNet]*

Characterizing Application Memory Error Vulnerability to Optimize Datacenter Cost via Heterogeneous-Reliability Memory

Yixin Luo Sriram Govindan^{*} Bikash Sharma^{*} Mark Santaniello^{*} Justin Meza Aman Kansal^{*} Jie Liu^{*} Badriddine Khessib^{*} Kushagra Vaid^{*} Onur Mutlu Carnegie Mellon University, yixinluo@cs.cmu.edu, {meza, onur}@cmu.edu *Microsoft Corporation, {srgovin, bsharma, marksan, kansal, jie.liu, bkhessib, kvaid}@microsoft.com

Root Causes of Disturbance Errors

- Cause 1: Electromagnetic coupling
 - Toggling the wordline voltage briefly increases the voltage of adjacent wordlines
 - − Slightly opens adjacent rows → Charge leakage
- Cause 2: Conductive bridges
- Cause 3: Hot-carrier injection

Confirmed by at least one manufacturer

RowHammer Characterization Results

- 1. Most Modules Are at Risk
- 2. Errors vs. Vintage
- 3. Error = Charge Loss
- 4. Adjacency: Aggressor & Victim
- 5. Sensitivity Studies
- 6. Other Results in Paper
- 7. Solution Space

<u>Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM</u> <u>Disturbance Errors</u>, (Kim et al., ISCA 2014) 310

4. Adjacency: Aggressor & Victim



Note: For three modules with the most errors (only first bank)

Most aggressors & victims are adjacent

1 Access Interval (Aggressor)



Note: For three modules with the most errors (only first bank)

Less frequent accesses → Fewer errors

2 Refresh Interval



Note: Using three modules with the most errors (only first bank)

More frequent refreshes \rightarrow Fewer errors





Errors affected by data stored in other cells

6. Other Results (in Paper)

- Victim Cells ≠ Weak Cells (i.e., leaky cells)
 Almost no overlap between them
- Errors not strongly affected by temperature
 Default temperature: 50°C
 - At 30°C and 70°C, number of errors changes <15%
- Errors are repeatable
 - Across ten iterations of testing, >70% of victim cells had errors in every iteration

6. Other Results (in Paper) cont'd

- As many as 4 errors per cache-line

 Simple ECC (e.g., SECDED) cannot prevent all errors
- Number of cells & rows affected by aggressor

 Victims cells per aggressor: ≤110
 Victims rows per aggressor: ≤9
- Cells affected by two aggressors on either side
 - Very small fraction of victim cells (<100) have an error when either one of the aggressors is toggled

Some Potential Solutions





• Refresh frequently **Power, Performance**

• Sophisticated ECC

Cost, Power

• Access counters Cost, Power, Complexity

Naive Solutions

1 Throttle accesses to same row

- Limit access-interval: ≥500ns
- Limit number of accesses: $\leq 128K$ (=64ms/500ns)

2 Refresh more frequently

– Shorten refresh-interval by $\sim 7x$

Both naive solutions introduce significant overhead in performance and power

Apple's Patch for RowHammer

https://support.apple.com/en-gb/HT204934

Available for: OS X Mountain Lion v10.8.5, OS X Mavericks v10.9.5

Impact: A malicious application may induce memory corruption to escalate privileges

Description: A disturbance error, also known as Rowhammer, exists with some DDR3 RAM that could have led to memory corruption. This issue was mitigated by increasing memory refresh rates.

CVE-ID

CVE-2015-3693 : Mark Seaborn and Thomas Dullien of Google, working from original research by Yoongu Kim et al (2014)

HP and Lenovo released similar patches

Our Solution to RowHammer

- PARA: <u>Probabilistic Adjacent Row Activation</u>
- Key Idea
 - After closing a row, we activate (i.e., refresh) one of its neighbors with a low probability: p = 0.005
- Reliability Guarantee
 - When p=0.005, errors in one year: 9.4×10^{-14}
 - By adjusting the value of p, we can vary the strength of protection against errors

Advantages of PARA

- PARA refreshes rows infrequently
 - Low power
 - Low performance-overhead
 - Average slowdown: 0.20% (for 29 benchmarks)
 - Maximum slowdown: 0.75%
- PARA is stateless
 - Low cost
 - Low complexity
- PARA is an effective and low-overhead solution to prevent disturbance errors

Requirements for PARA

- If implemented in DRAM chip
 - Enough slack in timing parameters
 - Plenty of slack today:
 - Lee et al., "Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common Case," HPCA 2015.
 - Chang et al., "Understanding Latency Variation in Modern DRAM Chips," SIGMETRICS 2016.
 - Lee et al., "Design-Induced Latency Variation in Modern DRAM Chips," SIGMETRICS 2017.
 - Chang et al., "Understanding Reduced-Voltage Operation in Modern DRAM Devices," SIGMETRICS 2017.
- If implemented in memory controller
 - Better coordination between memory controller and DRAM
 - Memory controller should know which rows are physically adjacent

More on RowHammer Analysis

Yoongu Kim, Ross Daly, Jeremie Kim, Chris Fallin, Ji Hye Lee, Donghyuk Lee, Chris Wilkerson, Konrad Lai, and Onur Mutlu,
 "Flipping Bits in Memory Without Accessing Them: An

 Experimental Study of DRAM Disturbance Errors"
 Proceedings of the <u>41st International Symposium on Computer</u>
 <u>Architecture</u> (ISCA), Minneapolis, MN, June 2014.

 [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)] [Source Code and Data]

Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Yoongu Kim¹ Ross Daly^{*} Jeremie Kim¹ Chris Fallin^{*} Ji Hye Lee¹ Donghyuk Lee¹ Chris Wilkerson² Konrad Lai Onur Mutlu¹ ¹Carnegie Mellon University ²Intel Labs

Retrospective on RowHammer & Future

Onur Mutlu, "The RowHammer Problem and Other Issues We May Face as Memory Becomes Denser" Invited Paper in Proceedings of the Design, Automation, and Test in Europe Conference (DATE), Lausanne, Switzerland, March 2017. [Slides (pptx) (pdf)]

The RowHammer Problem and Other Issues We May Face as Memory Becomes Denser

Onur Mutlu ETH Zürich onur.mutlu@inf.ethz.ch https://people.inf.ethz.ch/omutlu

SAFARI https://people.inf.ethz.ch/omutlu/pub/rowhammer-and-other-memory-issues_date17.pdf 324
Challenge and Opportunity for Future

Fundamentally Secure, Reliable, Safe Computing Architectures

Future of Main Memory

• DRAM is becoming less reliable \rightarrow more vulnerable

Large-Scale Failure Analysis of DRAM Chips

- Analysis and modeling of memory errors found in all of Facebook's server fleet
- Justin Meza, Qiang Wu, Sanjeev Kumar, and Onur Mutlu, <u>"Revisiting Memory Errors in Large-Scale Production Data</u> <u>Centers: Analysis and Modeling of New Trends from the Field"</u> *Proceedings of the <u>45th Annual IEEE/IFIP International Conference on</u> <u>Dependable Systems and Networks</u> (DSN), Rio de Janeiro, Brazil, June 2015. [<u>Slides (pptx) (pdf)</u>] [DRAM Error Model]*

Revisiting Memory Errors in Large-Scale Production Data Centers: Analysis and Modeling of New Trends from the Field

> Justin Meza Qiang Wu* Sanjeev Kumar* Onur Mutlu Carnegie Mellon University * Facebook, Inc.

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DRAM Reliability Reducing



Chip density (Gb)

Aside: SSD Error Analysis in the Field

First large-scale field study of flash memory errors

 Justin Meza, Qiang Wu, Sanjeev Kumar, and Onur Mutlu, "A Large-Scale Study of Flash Memory Errors in the Field" Proceedings of the <u>ACM International Conference on</u> <u>Measurement and Modeling of Computer Systems</u> (SIGMETRICS), Portland, OR, June 2015. [Slides (pptx) (pdf)] [Coverage at ZDNet]

A Large-Scale Study of Flash Memory Failures in the Field

Justin Meza Carnegie Mellon University meza@cmu.edu Qiang Wu Facebook, Inc. qwu@fb.com Sanjeev Kumar Facebook, Inc. skumar@fb.com Onur Mutlu Carnegie Mellon University onur@cmu.edu

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Future of Main Memory

- DRAM is becoming less reliable \rightarrow more vulnerable
- Due to difficulties in DRAM scaling, other problems may also appear (or they may be going unnoticed)
- Some errors may already be slipping into the field
 - Read disturb errors (Rowhammer)
 - Retention errors
 - Read errors, write errors

```
• ...
```

These errors can also pose security vulnerabilities

DRAM Data Retention Time Failures

- Determining the data retention time of a cell/row is getting more difficult
- Retention failures may already be slipping into the field

Analysis of Retention Failures [ISCA'13]

 Jamie Liu, Ben Jaiyen, Yoongu Kim, Chris Wilkerson, and <u>Onur Mutlu</u>, "An Experimental Study of Data Retention Behavior in Modern DRAM <u>Devices: Implications for Retention Time Profiling Mechanisms</u>" *Proceedings of the <u>40th International Symposium on Computer Architecture</u> (ISCA), Tel-Aviv, Israel, June 2013. <u>Slides (ppt)</u> <u>Slides (pdf)</u>*

An Experimental Study of Data Retention Behavior in Modern DRAM Devices: Implications for Retention Time Profiling Mechanisms

Jamie Liu* Ben Jaiyen^{*} Yoongu Kim Carnegie Mellon University Carnegie Mellon University Carnegie Mellon University 5000 Forbes Ave. 5000 Forbes Ave. 5000 Forbes Ave. Pittsburgh, PA 15213 Pittsburgh, PA 15213 Pittsburgh, PA 15213 bjaiyen@alumni.cmu.edu jamiel@alumni.cmu.edu yoonguk@ece.cmu.edu Chris Wilkerson Onur Mutlu Intel Corporation Carnegie Mellon University 2200 Mission College Blvd. 5000 Forbes Ave. Santa Clara, CA 95054 Pittsburgh, PA 15213

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Two Challenges to Retention Time Profiling

Data Pattern Dependence (DPD) of retention time

Variable Retention Time (VRT) phenomenon

Two Challenges to Retention Time Profiling

- Challenge 1: Data Pattern Dependence (DPD)
 - Retention time of a DRAM cell depends on its value and the values of cells nearby it
 - □ When a row is activated, all bitlines are perturbed simultaneously



Data Pattern Dependence

- Electrical noise on the bitline affects reliable sensing of a DRAM cell
- The magnitude of this noise is affected by values of nearby cells via
 - □ Bitline-bitline coupling \rightarrow electrical coupling between adjacent bitlines
 - Bitline-wordline coupling → electrical coupling between each bitline and the activated wordline



Data Pattern Dependence

- Electrical noise on the bitline affects reliable sensing of a DRAM cell
- The magnitude of this noise is affected by values of nearby cells via
 - □ Bitline-bitline coupling \rightarrow electrical coupling between adjacent bitlines
 - Bitline-wordline coupling → electrical coupling between each bitline and the activated wordline

- Retention time of a cell depends on data patterns stored in nearby cells
 - \rightarrow need to find the worst data pattern to find worst-case retention time
 - \rightarrow this pattern is location dependent

Two Challenges to Retention Time Profiling

- Challenge 2: Variable Retention Time (VRT)
 - Retention time of a DRAM cell changes randomly over time
 - a cell alternates between multiple retention time states
 - Leakage current of a cell changes sporadically due to a charge trap in the gate oxide of the DRAM cell access transistor
 - When the trap becomes occupied, charge leaks more readily from the transistor's drain, leading to a short retention time
 - Called *Trap-Assisted Gate-Induced Drain Leakage*
 - This process appears to be a random process [Kim + IEEE TED'11]
 - Worst-case retention time depends on a random process
 → need to find the worst case despite this

Modern DRAM Retention Time Distribution



Newer device families have more weak cells than older ones Likely a result of technology scaling

An Example VRT Cell



Variable Retention Time



More on DRAM Retention Analysis

 Jamie Liu, Ben Jaiyen, Yoongu Kim, Chris Wilkerson, and <u>Onur Mutlu</u>, "An Experimental Study of Data Retention Behavior in Modern DRAM <u>Devices: Implications for Retention Time Profiling Mechanisms</u>" *Proceedings of the <u>40th International Symposium on Computer Architecture</u> (ISCA), Tel-Aviv, Israel, June 2013. <u>Slides (ppt)</u> <u>Slides (pdf)</u>*

An Experimental Study of Data Retention Behavior in Modern DRAM Devices: Implications for Retention Time Profiling Mechanisms

Jamie Liu* Ben Jaiyen^{*} Yoongu Kim Carnegie Mellon University Carnegie Mellon University Carnegie Mellon University 5000 Forbes Ave. 5000 Forbes Ave. 5000 Forbes Ave. Pittsburgh, PA 15213 Pittsburgh, PA 15213 Pittsburgh, PA 15213 bjaiyen@alumni.cmu.edu jamiel@alumni.cmu.edu yoonguk@ece.cmu.edu Chris Wilkerson Onur Mutlu Intel Corporation Carnegie Mellon University 2200 Mission College Blvd. 5000 Forbes Ave. Santa Clara, CA 95054 Pittsburgh, PA 15213

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Industry Is Writing Papers About It, Too

DRAM Process Scaling Challenges

Refresh

- · Difficult to build high-aspect ratio cell capacitors decreasing cell capacitance
- · Leakage current of cell access transistors increasing

✤ tWR

- · Contact resistance between the cell capacitor and access transistor increasing
- · On-current of the cell access transistor decreasing
- · Bit-line resistance increasing

VRT

Occurring more frequently with cell capacitance decreasing



Industry Is Writing Papers About It, Too

DRAM Process Scaling Challenges

* Refresh

Difficult to build high-aspect ratio cell capacitors decreasing cell capacitance
THE MEMORY FORUM 2014

Co-Architecting Controllers and DRAM to Enhance DRAM Process Scaling

Uksong Kang, Hak-soo Yu, Churoo Park, *Hongzhong Zheng, **John Halbert, **Kuljit Bains, SeongJin Jang, and Joo Sun Choi



Samsung Electronics, Hwasung, Korea / *Samsung Electronics, San Jose / **Intel

Mitigation of Retention Issues [SIGMETRICS'14]

Samira Khan, Donghyuk Lee, Yoongu Kim, Alaa Alameldeen, Chris Wilkerson, and Onur Mutlu, "The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study" Proceedings of the <u>ACM International Conference on Measurement and</u> *Modeling of Computer Systems (SIGMETRICS)*, Austin, TX, June 2014. [Slides (pptx) (pdf)] [Poster (pptx) (pdf)] [Full data sets]

The Efficacy of Error Mitigation Techniques for DRAM **Retention Failures: A Comparative Experimental Study**

Samira Khan[†]* samirakhan@cmu.edu

Donghyuk Lee[†] donghyuk1@cmu.edu

Chris Wilkerson*

Yoongu Kim[†] yoongukim@cmu.edu

Alaa R. Alameldeen* alaa.r.alameldeen@intel.com chris.wilkerson@intel.com

Onur Mutlu[†] onur@cmu.edu

*Intel Labs [†]Carnegie Mellon University

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Handling Data-Dependent Failures [DSN'16]

Samira Khan, Donghyuk Lee, Yoongu Kim, Alaa Alameldeen, Chris Wilkerson, and Onur Mutlu, "The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study" Proceedings of the <u>ACM International Conference on Measurement and</u> Modeling of Computer Systems (SIGMETRICS), Austin, TX, June 2014. [Slides (pptx) (pdf)] [Poster (pptx) (pdf)] [Full data sets]

PARBOR: An Efficient System-Level Technique to Detect Data-Dependent Failures in DRAM

*University of Virginia

Samira Khan^{*} Donghyuk Lee^{†‡} [†]Carnegie Mellon University Onur Mutlu*[†] [‡]Nvidia *ETH Zürich

Handling Data-Dependent Failures [CAL'16]

 Samira Khan, Chris Wilkerson, Donghyuk Lee, Alaa R. Alameldeen, and <u>Onur</u> <u>Mutlu</u>,

"A Case for Memory Content-Based Detection and Mitigation of Data-Dependent Failures in DRAM"

<u>IEEE Computer Architecture Letters</u> (CAL), November 2016.

A Case for Memory Content-Based Detection and Mitigation of Data-Dependent Failures in DRAM

Samira Khan*, Chris Wilkerson[†], Donghyuk Lee[‡], Alaa R. Alameldeen[†], Onur Mutlu^{*‡} *University of Virginia [†]Intel Labs [‡]Carnegie Mellon University ^{*}ETH Zürich

Handling Variable Retention Time [DSN'15]

 Moinuddin Qureshi, Dae Hyun Kim, Samira Khan, Prashant Nair, and Onur Mutlu,

"AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems"

Proceedings of the <u>45th Annual IEEE/IFIP International Conference on</u> <u>Dependable Systems and Networks</u> (**DSN**), Rio de Janeiro, Brazil, June 2015. [<u>Slides (pptx) (pdf)</u>]

AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems

Moinuddin K. Qureshi[†] Dae-Hyun Kim[†] [†]Georgia Institute of Technology {*moin, dhkim, pnair6*}@ece.gatech.edu Samira Khan[‡]

Prashant J. Nair[†] Onur Mutlu[‡] [‡]Carnegie Mellon University {*samirakhan, onur*}@*cmu.edu*

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Handling Both DPD and VRT [ISCA'17]

- Minesh Patel, Jeremie S. Kim, and <u>Onur Mutlu</u>,
 "The Reach Profiler (REAPER): Enabling the Mitigation of DRAM <u>Retention Failures via Profiling at Aggressive Conditions</u>" *Proceedings of the <u>44th International Symposium on Computer Architecture</u> (ISCA), Toronto, Canada, June 2017.*
- First experimental analysis of (mobile) LPDDR4 chips
- Analyzes the complex tradeoff space of retention time profiling
- Key idea: enable fast and robust profiling at higher refresh intervals & temp.

The Reach Profiler (REAPER): Enabling the Mitigation of DRAM Retention Failures via Profiling at Aggressive Conditions

Minesh Patel^{§‡} Jeremie S. Kim^{‡§} Onur Mutlu^{§‡} [§]ETH Zürich [‡]Carnegie Mellon University

Summary: Memory Reliability and Security

- Memory reliability is reducing
- Reliability issues open up security vulnerabilities
 - Very hard to defend against
- Rowhammer is an example
 - □ Its implications on system security research are tremendous & exciting
- Good news: We have a lot more to do.
- Understand: Solid methodologies for failure modeling and discovery
 Modeling based on real device data small scale and large scale
- Architect: Principled co-architecting of system and memory
 - Good partitioning of duties across the stack
- Design & Test: Principled electronic design, automation, testing
 - High coverage and good interaction with system reliability methods

If Time Permits: NAND Flash Vulnerabilities

 Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu,
 "Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives"

to appear in <u>Proceedings of the IEEE</u>, 2017.

Cai+, "Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis," DATE 2012.

Cai+, "Flash Correct-and-Refresh: Retention-Aware Error Management for Increased Flash Memory Lifetime," ICCD 2012.

Cai+, "Threshold Voltage Distribution in MLC NAND Flash Memory: Characterization, Analysis and Modeling," DATE 2013.

Cai+, "Error Analysis and Retention-Aware Error Management for NAND Flash Memory," Intel Technology Journal 2013.

Cai+, Program Interference in MLC NAND Flash Memory: Characterization, Modeling, and Mitigation," ICCD 2013.

Cai+, "Neighbor-Cell Assisted Error Correction for MLC NAND Flash Memories," SIGMETRICS 2014.

Cai+, "Data Retention in MLC NAND Flash Memory: Characterization, Optimization and Recovery," HPCA 2015.

Cai+, "Read Disturb Errors in MLC NAND Flash Memory: Characterization and Mitigation," DSN 2015.

Luo+, "WARM: Improving NAND Flash Memory Lifetime with Write-hotness Aware Retention Management," MSST 2015.

Meza+, "A Large-Scale Study of Flash Memory Errors in the Field," SIGMETRICS 2015.

Luo+, "Enabling Accurate and Practical Online Flash Channel Modeling for Modern MLC NAND Flash Memory," IEEE JSAC 2016.

Cai+, "Vulnerabilities in MLC NAND Flash Memory Programming: Experimental Analysis, Exploits, and Mitigation Techniques," HPCA 2017.

Fukami+, "Improving the Reliability of Chip-Off Forensic Analysis of NAND Flash Memory Devices," DFRWS EU 2017.

Cai+, "Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives," Proc. IEEE 2017.

Overview Paper on Flash Reliability

- Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu,
 - "Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives"

to appear in <u>Proceedings of the IEEE</u>, 2017.

Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives

Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu

Challenge and Opportunity for Future

Fundamentally Secure, Reliable, Safe Computing Architectures

NAND Flash Memory Reliability and Security

Upcoming Overview Paper

- Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu,
 - "Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives"

to appear in <u>Proceedings of the IEEE</u>, 2017.

Error Characterization, Mitigation, and Recovery in Flash Memory Based Solid State Drives

Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu



Evolution of NAND Flash Memory





Seaung Suk Lee, "Emerging Challenges in NAND Flash Technology", Flash Summit 2011 (Hynix)

- Flash memory is widening its range of applications
 - Portable consumer devices, laptop PCs and enterprise servers

Flash Challenges: Reliability and Endurance



E. Grochowski et al., "Future technology challenges for NAND flash and HDD products", Flash Memory Summit 2012

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NAND Flash Memory is Increasingly Noisy



Future NAND Flash-based Storage Architecture



Our Goals:

Build reliable error models for NAND flash memory

Design efficient reliability mechanisms based on the model

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NAND Flash Error Model



Experimentally characterize and model dominant errors

Cai et al., "Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis", **DATE 2012** Luo et al., "Enabling Accurate and Practical Online Flash Channel Modeling for Modern MLC NAND Flash Memory", **JSAC 2016**

Write



Cai et al., "Threshold voltage distribution in MLC NAND Flash Memory: Characterization, Analysis, and Modeling", **DATE 2013**

Cai et al., "Vulnerabilities in MLC NAND Flash Memory Programming: Experimental Analysis, Exploits, and Mitigation Techniques", **HPCA 2017**



Cai et al., "Program Interference in MLC NAND Flash Memory: Characterization, Modeling, and Mitigation", **ICCD 2013**

Cai et al., "Neighbor-Cell Assisted Error Correction in MLC NAND Flash Memories", **SIGMETRICS 2014**

Cai et al., "Read Disturb Errors in MLC NAND Flash Memory: Characterization and Mitigation", **DSN 2015** Cai et al., "Flash Correct-and-Refresh: Retention-aware error management for

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increased flash memory lifetime", ICCD 2012

Cai et al., "Error Analysis and Retention-Aware Error Management for NAND Flash Memory, **ITJ 2013**

Cai et al., "Data Retention in MLC NAND Flash Memory: Characterization, Optimization and Recovery" , **HPCA 2015**

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Read

Our Goals and Approach

Goals:

- Understand error mechanisms and develop reliable predictive models for MLC NAND flash memory errors
- Develop efficient error management techniques to mitigate errors and improve flash reliability and endurance
- Approach:
 - □ Solid experimental analyses of errors in real MLC NAND flash memory → drive the understanding and models
 - □ Understanding, models, and creativity → drive the new techniques
Experimental Testing Platform



[DATE 2012, ICCD 2012, DATE 2013, ITJ 2013, ICCD 2013, SIGMETRICS 2014, HPCA 2015, DSN 2015, MSST 2015, JSAC 2016, HPCA 2017, DFRWS 2017]

NAND Daughter Board

SAFARI Cai et al., FPGA-based Solid-State Drive prototyping platform, FCCM 2011. ³⁶¹

NAND Flash Error Types

- Four types of errors [Cai+, DATE 2012]
- Caused by common flash operations
 - Read errors
 - Erase errors
 - Program (interference) errors
- Caused by flash cell losing charge over time
 - Retention errors
 - Whether an error happens depends on required retention time
 - Especially problematic in MLC flash because threshold voltage window to determine stored value is smaller

Observations: Flash Error Analysis



- Raw bit error rate increases exponentially with P/E cycles
- Retention errors are dominant (>99% for 1-year ret. time)
- Retention errors increase with retention time requirement

SAFARI Cai et al., Error Patterns in MLC NAND Flash Memory, DATE 2012. ³⁶³

More on Flash Error Analysis

 Yu Cai, Erich F. Haratsch, Onur Mutlu, and Ken Mai, <u>"Error Patterns in MLC NAND Flash Memory:</u> <u>Measurement, Characterization, and Analysis"</u> *Proceedings of the Design, Automation, and Test in Europe* <u>Conference</u> (DATE), Dresden, Germany, March 2012. <u>Slides</u> (ppt)

Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis

Yu Cai¹, Erich F. Haratsch², Onur Mutlu¹ and Ken Mai¹ ¹Department of Electrical and Computer Engineering, Carnegie Mellon University, Pittsburgh, PA ²LSI Corporation, 1110 American Parkway NE, Allentown, PA ¹{yucai, onur, kenmai}@andrew.cmu.edu, ²erich.haratsch@lsi.com

Solution to Retention Errors

- Refresh periodically
- Change the period based on P/E cycle wearout
 - Refresh more often at higher P/E cycles
- Use a combination of in-place and remapping-based refresh

Flash Correct-and-Refresh: Retention-Aware Error Management for Increased Flash Memory Lifetime

Yu Cai¹, Gulay Yalcin², Onur Mutlu¹, Erich F. Haratsch³, Adrian Cristal², Osman S. Unsal² and Ken Mai¹ ¹DSSC, Department of Electrical and Computer Engineering, Carnegie Mellon University, Pittsburgh, PA ²Barcelona Supercomputing Center, C/Jordi Girona 29, Barcelona, Spain ³LSI Corporation, 1110 American Parkway NE, Allentown, PA

One Issue: Read Disturb in Flash Memory

All scaled memories are prone to read disturb errors

NAND Flash Memory Background



Flash Cell Array



Flash Cell



Floating Gate Transistor (Flash Cell)



Flash Read



Flash Pass-Through





Read from Flash Cell Array



Read Disturb Problem: "Weak Programming" Effect



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Read Disturb Problem: "Weak Programming" Effect



Executive Summary



- Read disturb errors limit flash memory lifetime today
 - Apply a high pass-through voltage (V_{pass}) to multiple pages on a read
 - Repeated application of V_{pass} can alter stored values in unread pages
- We characterize read disturb on real NAND flash chips
 - Slightly lowering V_{pass} greatly reduces read disturb errors
 - Some flash cells are more prone to read disturb
- Technique 1: Mitigate read disturb errors online
 - V_{pass} Tuning dynamically finds and applies a lowered V_{pass} per block
 Flash memory lifetime improves by 21%
- Technique 2: Recover after failure to prevent data loss
 - Read Disturb Oriented Error Recovery (RDR) selectively corrects cells more susceptible to read disturb errors

Reduces raw bit error rate (RBER) by up to 36%
 SAFARI

More on Flash Read Disturb Errors

 Yu Cai, Yixin Luo, Saugata Ghose, Erich F. Haratsch, Ken Mai, and Onur Mutlu,
 "Read Disturb Errors in MLC NAND Flash Memory: Characterization and Mitigation"
 Proceedings of the <u>45th Annual IEEE/IFIP International</u>
 <u>Conference on Dependable Systems and Networks</u> (DSN), Rio de Janeiro, Brazil, June 2015.

Read Disturb Errors in MLC NAND Flash Memory: Characterization, Mitigation, and Recovery

Yu Cai, Yixin Luo, Saugata Ghose, Erich F. Haratsch*, Ken Mai, Onur Mutlu Carnegie Mellon University, *Seagate Technology yucaicai@gmail.com, {yixinluo, ghose, kenmai, onur}@cmu.edu

Large-Scale Flash SSD Error Analysis

- First large-scale field study of flash memory errors
- Justin Meza, Qiang Wu, Sanjeev Kumar, and Onur Mutlu, "A Large-Scale Study of Flash Memory Errors in the Field" Proceedings of the <u>ACM International Conference on Measurement and</u> <u>Modeling of Computer Systems</u> (SIGMETRICS), Portland, OR, June 2015. [Slides (pptx) (pdf)] [Coverage at ZDNet] [Coverage on The Register] [Coverage on TechSpot] [Coverage on The Tech Report]

A Large-Scale Study of Flash Memory Failures in the Field

Justin Meza Carnegie Mellon University meza@cmu.edu Qiang Wu Facebook, Inc. qwu@fb.com Sanjeev Kumar Facebook, Inc. skumar@fb.com Onur Mutlu Carnegie Mellon University onur@cmu.edu

Another Time: NAND Flash Vulnerabilities

Onur Mutlu,

"Error Analysis and Management for MLC NAND Flash Memory"

Technical talk at <u>Flash Memory Summit 2014</u> (FMS), Santa Clara, CA, August 2014. <u>Slides (ppt) (pdf)</u>

Cai+, "Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis," DATE 2012. Cai+, "Flash Correct-and-Refresh: Retention-Aware Error Management for Increased Flash Memory Lifetime," ICCD 2012.

Cai+, "Threshold Voltage Distribution in MLC NAND Flash Memory: Characterization, Analysis and Modeling," DATE 2013.

Cai+, "Error Analysis and Retention-Aware Error Management for NAND Flash Memory," Intel Technology Journal 2013.

Cai+, Program Interference in MLC NAND Flash Memory: Characterization, Modeling, and Mitigation," ICCD 2013.

Cai+, "Neighbor-Cell Assisted Error Correction for MLC NAND Flash Memories," SIGMETRICS 2014.

Cai+, "Data Retention in MLC NAND Flash Memory: Characterization, Optimization and Recovery," HPCA 2015.

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Luo+, "WARM: Improving NAND Flash Memory Lifetime with Write-hotness Aware Retention Management," MSST 2015.

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Luo+, "Enabling Accurate and Practical Online Flash Channel Modeling for Modern MLC NAND Flash Memory," IEEE JSAC 2016.

Cai+, "Vulnerabilities in MLC NAND Flash Memory Programming: Experimental Analysis, Exploits, and Mitigation Techniques," HPCA 2017.

Fukami+, "Improving the Reliability of Chip-Off Forensic Analysis of NAND Flash Memory Devices," DFRWS EU 2017.

Flash Memory Programming Vulnerabilities

 Yu Cai, Saugata Ghose, Yixin Luo, Ken Mai, <u>Onur Mutlu</u>, and Erich F. Haratsch,
 <u>"Vulnerabilities in MLC NAND Flash Memory Programming:</u> <u>Experimental Analysis, Exploits, and Mitigation Techniques"</u> *Proceedings of the <u>23rd International Symposium on High-Performance</u> <u>Computer Architecture</u> (<i>HPCA*) Industrial Session, Austin, TX, USA, February 2017.
 [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

Vulnerabilities in MLC NAND Flash Memory Programming: Experimental Analysis, Exploits, and Mitigation Techniques

Yu Cai[†]

Saugata Ghose[†] Yixin Luo^{‡†} [†]Carnegie Mellon University Ken Mai[†] Onur Mutlu^{§†} Erich F. Haratsch[‡] [‡]Seagate Technology [§]ETH Zürich

Other Works on Flash Memory

NAND Flash Error Model



Experimentally characterize and model dominant errors

Cai et al., "Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis", **DATE 2012** Luo et al., "Enabling Accurate and Practical Online Flash Channel Modeling for Modern MLC NAND Flash Memory", **JSAC 2016**

Write



Cai et al., "Threshold voltage distribution in MLC NAND Flash Memory: Characterization, Analysis, and Modeling", **DATE 2013**

Cai et al., "Vulnerabilities in MLC NAND Flash Memory Programming: Experimental Analysis, Exploits, and Mitigation Techniques", **HPCA 2017**



Cai et al., "Program Interference in MLC NAND Flash Memory: Characterization, Modeling, and Mitigation", **ICCD 2013**

Cai et al., "Neighbor-Cell Assisted Error Correction in MLC NAND Flash Memories", **SIGMETRICS 2014**

Cai et al., "Read Disturb Errors in MLC NAND Flash Memory: Characterization and Mitigation", **DSN 2015** Retention



Cai et al., "Flash Correct-and-Refresh: Retention-aware error management for increased flash memory lifetime", **ICCD 2012**

Cai et al., "Error Analysis and Retention-Aware Error Management for NAND Flash Memory, **ITJ 2013**

Cai et al., "Data Retention in MLC NAND Flash Memory: Characterization, Optimization and Recovery" **, HPCA 2015**

Threshold Voltage Distribution

 Yu Cai, Erich F. Haratsch, Onur Mutlu, and Ken Mai, "Threshold Voltage Distribution in MLC NAND Flash Memory: Characterization, Analysis and Modeling" Proceedings of the Design, Automation, and Test in Europe <u>Conference</u> (DATE), Grenoble, France, March 2013. Slides (ppt)

Threshold Voltage Distribution in MLC NAND Flash Memory: Characterization, Analysis, and Modeling

Yu Cai¹, Erich F. Haratsch², Onur Mutlu¹ and Ken Mai¹ ¹DSSC, Department of Electrical and Computer Engineering, Carnegie Mellon University, Pittsburgh, PA ²LSI Corporation, 1110 American Parkway NE, Allentown, PA ¹{yucai, onur, kenmai}@andrew.cmu.edu, ²erich.haratsch@lsi.com

Program Interference and Vref Prediction

 Yu Cai, Onur Mutlu, Erich F. Haratsch, and Ken Mai, "Program Interference in MLC NAND Flash Memory: Characterization, Modeling, and Mitigation" Proceedings of the <u>31st IEEE International Conference on</u> <u>Computer Design</u> (ICCD), Asheville, NC, October 2013. Slides (pptx) (pdf) Lightning Session Slides (pdf)

Program Interference in MLC NAND Flash Memory: Characterization, Modeling, and Mitigation

Yu Cai¹, Onur Mutlu¹, Erich F. Haratsch² and Ken Mai¹ 1. Data Storage Systems Center, Department of Electrical and Computer Engineering, Carnegie Mellon University, Pittsburgh, PA 2. LSI Corporation, San Jose, CA yucaicai@gmail.com, {omutlu, kenmai}@andrew.cmu.edu

Neighbor-Assisted Error Correction

 Yu Cai, Gulay Yalcin, Onur Mutlu, Eric Haratsch, Osman Unsal, Adrian Cristal, and Ken Mai,
 "Neighbor-Cell Assisted Error Correction for MLC NAND Flash Memories"
 Proceedings of the <u>ACM International Conference on</u> <u>Measurement and Modeling of Computer Systems</u>

(SIGMETRICS), Austin, TX, June 2014. Slides (ppt) (pdf)

Neighbor-Cell Assisted Error Correction for MLC NAND Flash Memories

Yu Cai¹, Gulay Yalcin², Onur Mutlu¹, Erich F. Haratsch⁴, Osman Unsal², Adrian Cristal^{2,3}, and Ken Mai¹ ¹Electrical and Computer Engineering Department, Carnegie Mellon University ²Barcelona Supercomputing Center, Spain ³IIIA – CSIC – Spain National Research Council ⁴LSI Corporation yucaicai@gmail.com, {omutlu, kenmai}@ece.cmu.edu, {gulay.yalcin, adrian.cristal, osman.unsal}@bsc.es

Data Retention

 Yu Cai, Yixin Luo, Erich F. Haratsch, Ken Mai, and Onur Mutlu, "Data Retention in MLC NAND Flash Memory: Characterization, Optimization and Recovery" Proceedings of the <u>21st International Symposium on High-Performance</u> <u>Computer Architecture</u> (HPCA), Bay Area, CA, February 2015. [Slides (pptx) (pdf)]

Data Retention in MLC NAND Flash Memory: Characterization, Optimization, and Recovery

Yu Cai, Yixin Luo, Erich F. Haratsch^{*}, Ken Mai, Onur Mutlu Carnegie Mellon University, ^{*}LSI Corporation yucaicai@gmail.com, yixinluo@cs.cmu.edu, erich.haratsch@lsi.com, {kenmai, omutlu}@ece.cmu.edu

SSD Error Analysis in the Field

- First large-scale field study of flash memory errors
- Justin Meza, Qiang Wu, Sanjeev Kumar, and <u>Onur Mutlu</u>, <u>"A Large-Scale Study of Flash Memory Errors in the Field"</u> *Proceedings of the <u>ACM International Conference on</u> <u>Measurement and Modeling of Computer Systems</u> (SIGMETRICS), Portland, OR, June 2015. [Slides (pptx) (pdf)] [Coverage at ZDNet] [Coverage on The Register] [Coverage on TechSpot] [Coverage on The Tech <u>Report</u>]*

A Large-Scale Study of Flash Memory Failures in the Field

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Flash Memory Programming Vulnerabilities

 Yu Cai, Saugata Ghose, Yixin Luo, Ken Mai, <u>Onur Mutlu</u>, and Erich F. Haratsch,
 <u>"Vulnerabilities in MLC NAND Flash Memory Programming:</u> <u>Experimental Analysis, Exploits, and Mitigation Techniques"</u> *Proceedings of the <u>23rd International Symposium on High-Performance</u> <u>Computer Architecture</u> (<i>HPCA*) Industrial Session, Austin, TX, USA, February 2017.
 [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

Vulnerabilities in MLC NAND Flash Memory Programming: Experimental Analysis, Exploits, and Mitigation Techniques

Yu Cai[†]

Saugata Ghose[†] Yixin Luo^{‡†} [†]Carnegie Mellon University Ken Mai[†] Onur Mutlu^{§†} Erich F. Haratsch[‡] [‡]Seagate Technology [§]ETH Zürich

Accurate and Online Channel Modeling

 Yixin Luo, Saugata Ghose, Yu Cai, Erich F. Haratsch, and <u>Onur Mutlu</u>, <u>"Enabling Accurate and Practical Online Flash Channel Modeling</u> <u>for Modern MLC NAND Flash Memory"</u>

to appear in <u>IEEE Journal on Selected Areas in Communications</u> (JSAC), 2016.

Enabling Accurate and Practical Online Flash Channel Modeling for Modern MLC NAND Flash Memory

Yixin Luo, Saugata Ghose, Yu Cai, Erich F. Haratsch, Onur Mutlu

More on DRAM Refresh

Tackling Refresh: Solutions

Parallelize refreshes with accesses [Chang+ HPCA'14]

- Eliminate unnecessary refreshes [Liu+ ISCA'12]
 - Exploit device characteristics
 - Exploit data and application characteristics
- Reduce refresh rate and detect+correct errors that occur [Khan+ SIGMETRICS'14]
- Understand retention time behavior in DRAM [Liu+ ISCA'13]

Summary: Refresh-Access Parallelization

- DRAM refresh interferes with memory accesses
 - Degrades system performance and energy efficiency
 - Becomes exacerbated as DRAM density increases
- <u>Goal</u>: Serve memory accesses in parallel with refreshes to reduce refresh interference on demand requests
- Our mechanisms:
 - 1. Enable more parallelization between refreshes and accesses across different banks with new per-bank refresh scheduling algorithms
 - 2. Enable serving accesses concurrently with refreshes in the same bank by exploiting parallelism across DRAM subarrays
- Improve system performance and energy efficiency for a wide variety of different workloads and DRAM densities
 - 20.2% and 9.0% for 8-core systems using 32Gb DRAM at low cost
 - Very close to the ideal scheme without refreshes

Chang+, "Improving DRAM Performance by Parallelizing Refreshes with Accesses," HPCA 2014.

Refresh Penalty



Refresh delays requests by 100s of ns

Existing Refresh Modes

All-bank refresh in commodity DRAM (DDRx)



Shortcomings of Per-Bank Refresh

- <u>Problem 1</u>: Refreshes to different banks are scheduled in a strict round-robin order
 - The static ordering is hardwired into DRAM chips
 - Refreshes busy banks with many queued requests when other banks are idle
- <u>Key idea</u>: Schedule per-bank refreshes to idle banks opportunistically in a dynamic order

Our First Approach: DARP

- Dynamic Access-Refresh Parallelization (DARP)
 - An improved scheduling policy for per-bank refreshes
 - Exploits refresh scheduling flexibility in DDR DRAM
- <u>Component 1</u>: Out-of-order per-bank refresh
 - Avoids poor static scheduling decisions
 - Dynamically issues per-bank refreshes to idle banks
- <u>Component 2</u>: Write-Refresh Parallelization
 - Avoids refresh interference on latency-critical reads
 - Parallelizes refreshes with a batch of writes

Shortcomings of Per-Bank Refresh

<u>Problem 2</u>: Banks that are being refreshed cannot concurrently serve memory requests


Shortcomings of Per-Bank Refresh

- <u>Problem 2</u>: Refreshing banks cannot concurrently serve memory requests
- <u>Key idea</u>: Exploit subarrays within a bank to parallelize refreshes and accesses across subarrays



Methodology



- **<u>100 workloads</u>**: SPEC CPU2006, STREAM, TPC-C/H, random access
- **System performance metric**: Weighted speedup

Comparison Points

- All-bank refresh [DDR3, LPDDR3, ...]
- Per-bank refresh [LPDDR3]
- Elastic refresh [Stuecheli et al., MICRO '10]:
 - Postpones refreshes by a time delay based on the predicted rank idle time to avoid interference on memory requests
 - Proposed to schedule all-bank refreshes without exploiting per-bank refreshes
 - Cannot parallelize refreshes and accesses within a rank
- Ideal (no refresh)

System Performance



2. Consistent system performance improvement across DRAM densities (within **0.9%, 1.2%, and 3.8%** of ideal)

Energy Efficiency



More Information on Refresh-Access Parallelization

 Kevin Chang, Donghyuk Lee, Zeshan Chishti, Alaa Alameldeen, Chris Wilkerson, Yoongu Kim, and Onur Mutlu,
 "Improving DRAM Performance by Parallelizing Refreshes with Accesses"
 Proceedings of the <u>20th International Symposium on High-Performance</u> Computer Architecture (HPCA), Orlando, FL, February 2014.

[Summary] [Slides (pptx) (pdf)]

Reducing Performance Impact of DRAM Refresh by Parallelizing Refreshes with Accesses

Kevin Kai-Wei Chang Donghyuk Lee Zeshan Chishti† Alaa R. Alameldeen† Chris Wilkerson† Yoongu Kim Onur Mutlu Carnegie Mellon University †Intel Labs

Tackling Refresh: Solutions

- Parallelize refreshes with accesses [Chang+ HPCA'14]
- Eliminate unnecessary refreshes [Liu+ ISCA'12]
 - Exploit device characteristics
 - Exploit data and application characteristics
- Reduce refresh rate and detect+correct errors that occur [Khan+ SIGMETRICS'14]
- Understand retention time behavior in DRAM [Liu+ ISCA'13]

Most Refreshes Are Unnecessary

Retention Time Profile of DRAM looks like this:

64-128ms

>256ms

128-256ms

RAIDR: Eliminating Unnecessary Refreshes

64-128ms >256ms 1.25KB storage in controller for 32GB DRAM memory 128-256ms

Can reduce refreshes by ~75%

 \rightarrow reduces energy consumption and improves performance

SAFARI Liu et al., "RAIDR: Retention-Aware Intelligent DRAM Refresh," ISCA 2012.

RAIDR: Baseline Design



Refresh control is in DRAM in today's auto-refresh systems RAIDR can be implemented in either the controller or DRAM

RAIDR in Memory Controller: Option 1



Overhead of RAIDR in DRAM controller: 1.25 KB Bloom Filters, 3 counters, additional commands issued for per-row refresh (all accounted for in evaluations)

RAIDR in DRAM Chip: Option 2



Overhead of RAIDR in DRAM chip: Per-chip overhead: 20B Bloom Filters, 1 counter (4 Gbit chip) Total overhead: 1.25KB Bloom Filters, 64 counters (32 GB DRAM)

RAIDR: Results and Takeaways

- System: 32GB DRAM, 8-core; SPEC, TPC-C, TPC-H workloads
- RAIDR hardware cost: 1.25 kB (2 Bloom filters)
- Refresh reduction: 74.6%
- Dynamic DRAM energy reduction: 16%
- Idle DRAM power reduction: 20%
- Performance improvement: 9%
- Benefits increase as DRAM scales in density



DRAM Device Capacity Scaling: Performance



SAFARI Liu et al., "RAIDR: Retention-Aware Intelligent DRAM Refresh," ISCA 2012.

DRAM Device Capacity Scaling: Energy



SAFARI Liu et al., "RAIDR: Retention-Aware Intelligent DRAM Refresh," ISCA 2012.

RAIDR: Eliminating Unnecessary Refreshes

- Observation: Most DRAM rows can be refreshed much less often without losing data [Kim+, EDL'09][Liu+ ISCA'13] 10
- Key idea: Refresh rows containing weak cells more frequently, other rows less frequently

1. Profiling: Profile retention time of all rows



Auto RAIDR

8 Gb

20

0

4 Gb

50%

64 Gb

32 Gb

16 Gb

Device capacity

2. Binning: Store rows into bins by retention time in memory controller

Efficient storage with Bloom Filters (only 1.25KB for 32GB memory)

3. Refreshing: Memory controller refreshes rows in different bins at

- - Benefits increase with DRAM capacity

Liu et al., "RAIDR: Retention-Aware Intelligent DRAM Refresh," ISCA 2012.

More on RAIDR

 Jamie Liu, Ben Jaiyen, Richard Veras, and Onur Mutlu, "RAIDR: Retention-Aware Intelligent DRAM Refresh" Proceedings of the <u>39th International Symposium on</u> <u>Computer Architecture</u> (ISCA), Portland, OR, June 2012. <u>Slides (pdf)</u>

RAIDR: Retention-Aware Intelligent DRAM Refresh

Jamie Liu Ben Jaiyen Richard Veras Onur Mutlu Carnegie Mellon University

Tackling Refresh: Solutions

- Parallelize refreshes with accesses [Chang+ HPCA'14]
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- Reduce refresh rate and detect+correct errors that occur [Khan+ SIGMETRICS'14]

Understand retention time behavior in DRAM [Liu+ ISCA'13]

SAFARI

Motivation: Understanding Retention

- Past works require accurate and reliable measurement of retention time of each DRAM row
 - To maintain data integrity while reducing refreshes
- Assumption: worst-case retention time of each row can be determined and stays the same at a given temperature
 - Some works propose writing all 1's and 0's to a row, and measuring the time before data corruption
- Question:
 - Can we reliably and accurately determine retention times of all DRAM rows?

Two Challenges to Retention Time Profiling

Data Pattern Dependence (DPD) of retention time

Variable Retention Time (VRT) phenomenon

An Example VRT Cell



VRT: Implications on Profiling Mechanisms

- Problem 1: There does not seem to be a way of determining if a cell exhibits VRT without actually observing a cell exhibiting VRT
 - VRT is a memoryless random process [Kim+ JJAP 2010]
- Problem 2: VRT complicates retention time profiling by DRAM manufacturers
 - Exposure to very high temperatures can induce VRT in cells that were not previously susceptible
 - \rightarrow can happen during soldering of DRAM chips
 - \rightarrow manufacturer's retention time profile may not be accurate
- One option for future work: Use ECC to continuously profile DRAM online while aggressively reducing refresh rate
 - Need to keep ECC overhead in check

More on DRAM Retention Analysis

 Jamie Liu, Ben Jaiyen, Yoongu Kim, Chris Wilkerson, and <u>Onur Mutlu</u>, "An Experimental Study of Data Retention Behavior in Modern DRAM <u>Devices: Implications for Retention Time Profiling Mechanisms</u>" *Proceedings of the <u>40th International Symposium on Computer Architecture</u> (ISCA), Tel-Aviv, Israel, June 2013. <u>Slides (ppt)</u> <u>Slides (pdf)</u>*

An Experimental Study of Data Retention Behavior in Modern DRAM Devices: Implications for Retention Time Profiling Mechanisms

Jamie Liu* Ben Jaiyen^{*} Yoongu Kim Carnegie Mellon University Carnegie Mellon University Carnegie Mellon University 5000 Forbes Ave. 5000 Forbes Ave. 5000 Forbes Ave. Pittsburgh, PA 15213 Pittsburgh, PA 15213 Pittsburgh, PA 15213 bjaiyen@alumni.cmu.edu jamiel@alumni.cmu.edu yoonguk@ece.cmu.edu Chris Wilkerson Onur Mutlu Intel Corporation Carnegie Mellon University 2200 Mission College Blvd. 5000 Forbes Ave. Santa Clara, CA 95054 Pittsburgh, PA 15213

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Tackling Refresh: Solutions

- Parallelize refreshes with accesses [Chang+ HPCA'14]
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Reduce refresh rate and detect+correct errors that occur [Khan+ SIGMETRICS'14]

Understand retention time behavior in DRAM [Liu+ ISCA'13]

Towards an Online Profiling System

Key Observations:

- Testing alone cannot detect all possible failures
- Combination of ECC and other mitigation techniques is much more effective
 - But degrades performance
- Testing can help to reduce the ECC strength
 - Even when starting with a higher strength ECC

Khan+, "The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study," SIGMETRICS 2014.

Towards an Online Profiling System



More on Online Profiling of DRAM

Samira Khan, Donghyuk Lee, Yoongu Kim, Alaa Alameldeen, Chris Wilkerson, and Onur Mutlu, "The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study" Proceedings of the <u>ACM International Conference on Measurement and</u> *Modeling of Computer Systems (SIGMETRICS)*, Austin, TX, June 2014. [Slides (pptx) (pdf)] [Poster (pptx) (pdf)] [Full data sets]

The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study

Samira Khan[†]* samirakhan@cmu.edu

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Onur Mutlu[†] onur@cmu.edu

*Intel Labs [†]Carnegie Mellon University

How Do We Make RAIDR Work in the Presence of the VRT Phenomenon?

Making RAIDR Work w/ Online Profiling & ECC

 Moinuddin Qureshi, Dae Hyun Kim, Samira Khan, Prashant Nair, and Onur Mutlu,

"AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems"

Proceedings of the <u>45th Annual IEEE/IFIP International Conference on</u> <u>Dependable Systems and Networks</u> (**DSN**), Rio de Janeiro, Brazil, June 2015. [<u>Slides (pptx) (pdf)</u>]

AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems

Moinuddin K. Qureshi[†] Dae-Hyun Kim[†] [†]Georgia Institute of Technology {*moin, dhkim, pnair6*}@ece.gatech.edu Samira Khan[‡]

Prashant J. Nair[†] Onur Mutlu[‡] [‡]Carnegie Mellon University {*samirakhan, onur*}@*cmu.edu*

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AVATAR

Insight: Avoid retention failures \rightarrow Upgrade row on ECC error Observation: Rate of VRT >> Rate of soft error (50x-2500x)



AVATAR mitigates VRT by increasing refresh rate on error

RESULTS: REFRESH SAVINGS



Retention Testing Once a Year can revert refresh saving from 60% to 70%



AVATAR reduces refresh by 60%-70%, similar to multi rate refresh but with VRT tolerance

SPEEDUP



AVATAR gets 2/3rd the performance of NoRefresh. More gains at higher capacity nodes

ENERGY DELAY PRODUCT



AVATAR reduces EDP,

Significant reduction at higher capacity nodes

Making RAIDR Work w/ Online Profiling & ECC

 Moinuddin Qureshi, Dae Hyun Kim, Samira Khan, Prashant Nair, and Onur Mutlu,

"AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems"

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AVATAR: A Variable-Retention-Time (VRT) Aware Refresh for DRAM Systems

Moinuddin K. Qureshi[†] Dae-Hyun Kim[†] [†]Georgia Institute of Technology {*moin, dhkim, pnair6*}@ece.gatech.edu Samira Khan[‡]

Prashant J. Nair[†] Onur Mutlu[‡] [‡]Carnegie Mellon University {*samirakhan, onur*}@*cmu.edu*

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DRAM Refresh: Summary and Conclusions

- DRAM refresh is a critical challenge
 - in scaling DRAM technology efficiently to higher capacities
- Discussed several promising solution directions
 - □ Parallelize refreshes with accesses [Chang+ HPCA'14]
 - □ Eliminate unnecessary refreshes [Liu+ ISCA'12]
 - Reduce refresh rate and detect+correct errors that occur [Khan+ SIGMETRICS'14]
- Examined properties of retention time behavior [Liu+ ISCA'13]
 - Enable realistic VRT-Aware refresh techniques [Qureshi+ DSN'15]
- Many avenues for overcoming DRAM refresh challenges
 - Handling DPD/VRT phenomena
 - Enabling online retention time profiling and error mitigation
 - Exploiting application behavior

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Other Backup Slides
Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand

Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, Onur Mutlu











Google

Consumer Devices



Consumer devices are everywhere!

Energy consumption is a first-class concern in consumer devices



Popular Google Consumer Workloads



Chrome

Google's web browser



TensorFlow Mobile

Google's machine learning framework



Google's video codec



Energy Cost of Data Movement

Ist key observation: 62.7% of the total system energy is spent on data movement



Processing-in-Memory (PIM)

Potential solution: move computation close to data

Challenge: limited area and energy budget



Using PIM to Reduce Data Movement

2nd key observation: a significant fraction of data movement often comes from simple functions

We can design lightweight logic to implement these <u>simple functions</u> in <u>memory</u>

Small embedded low-power core



Small fixed-function accelerators



Offloading to PIM logic reduces energy by 55.4% and improves performance by 54.2% on average

Goals

Understand the data movement related bottlenecks in modern consumer workloads

2 Analyze opportunities to mitigate data movement by using processing-in-memory (PIM)

3 Design PIM logic that can maximize energy efficiency given the limited area and energy budget in consumer devices



Outline

- Introduction
- Background
- Analysis Methodology
- Workload Analysis
- Evaluation
- Conclusion

Potential Solution to Address Data Movement

- Processing-in-Memory (PIM)
 - A potential solution to reduce data movement
 - Idea: move computation close to data
 - **Reduces data movement**
 - **Exploits large in-memory bandwidth**
 - **Exploits shorter access latency to memory**
- Enabled by recent advances in 3D-stacked memory



Outline

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Workload Analysis Methodology

- Workload Characterization
 - Chromebook with an Intel Celeron SoC and 2GB of DRAM



- Extensively use performance counters within SoC
- Energy Model
 - Sum of the energy consumption within the CPU, all caches, off-chip interconnects, and DRAM



PIM Logic Implementation



Workload Analysis



Chrome Google's web browser



Google's machine learning framework





Workload Analysis



Chrome

Google's web browser



VP9 VouTube Video Playback Google's video codec



How Chrome Renders a Web Page



How Chrome Renders a Web Page



Browser Analysis

- To satisfy user experience, the browser must provide:
 - Fast loading of webpages
 - Smooth scrolling of webpages
 - Quick switching between browser tabs
- We focus on two important user interactions:
 - I) Page Scrolling
 - 2) Tab Switching
 - Both include page loading

Scrolling



What Does Happen During Scrolling?



Scrolling Energy Analysis



41.9% of page scrolling energy is spent on texture tiling and color blitting

Scrolling a Google Docs Web Page



Scrolling a Google Docs Web Page



Can we use PIM to mitigate the data movement cost for texture tiling and color blitting?





Texture tiling is a good candidate for PIM execution





Can We Implement Texture Tiling in PIM Logic?



Requires simple primitives: memcopy, bitwise operations, and simple arithmetic operations



9.4% of the area available for PIM logic

Accelerator 7.1% of the area

PIM

available for PIM logic

PIM core and PIM accelerator are feasible to implement in-memory Texture Tiling

Color Blitting Analysis

Generates a large amount of data movement Accounts for 19.1% of the total system energy during scrolling

Color blitting is a good candidate for PIM execution

Requires low-cost operations: Memset, simple arithmetic, and shift operations

It is feasible to implement color blitting in PIM core and PIM accelerator

Scrolling Wrap Up

Texture tiling and color blitting account for a significant portion (41.9%) of energy consumption

37.7% of total system energy goes to data movement generated by these functions

Both functions can benefit significantly from PIM execution





Tab Switching



What Happens During Tab Switching?

- Chrome employs a multi-process architecture
 - Each tab is a separate process



- Main operations during tab switching:
 - Context switch
 - Load the new page

Memory Consumption

- Primary concerns during tab switching:
 - How fast a new tab loads and becomes interactive
 - Memory consumption

Chrome uses compression to reduce each tab's memory footprint



Data Movement Study

• To study data movement during tab switching, we emulate a user switching through 50 tabs

We make two key observations:

Compression and decompression contribute to 8.1% of the total system energy

> **I 9.6 GB** of data moves between CPU and ZRAM

2

Can We Use PIM to Mitigate the Cost?



PIM core and PIM accelerator are feasible to implement in-memory compression/decompression

Tab Switching Wrap Up

A large amount of data movement happens during tab switching as Chrome attempts to compress and decompress tabs

Both functions can benefit from PIM execution and can be implemented as PIM logic

Workload Analysis



Chrome Google's web browser



Google's machine learning framework





Workload Analysis



Chrome Google's web browser



Google's machine learning framework





TensorFlow Mobile



57.3% of the inference energy is spent on data movement

54.4% of the data movement energy comes from packing/unpacking and quantization



Packing



A simple data reorganization process that requires simple arithmetic

Quantization



A simple data conversion operation that requires shift, addition, and multiplication operations




inference execution time

A simple data conversion operation that requires shift, addition, and multiplication operations

Video Playback and Capture





Majority of energy is spent on data movement

Majority of data movement comes from simple functions in decoding and encoding pipelines



Outline

- Introduction
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Evaluation Methodology

- System Configuration (gem5 Simulator)
 - SoC: 4 OoO cores, 8-wide issue, 64 kB Ll cache, 2MB L2 cache
 - PIM Core: I core per vault, I-wide issue, 4-wide SIMD, 32kB LI cache
 - **3D-Stacked Memory: 2GB cube, 16 vaults per cube**
 - Internal Bandwidth: 256GB/S
 - Off-Chip Channel Bandwidth: 32 GB/s
 - Baseline Memory: LPDDR3, 2GB, FR-FCFS scheduler
- We study each target in isolation and emulate each separately and run them in our simulator 40 SAFARI

Normalized Energy

© CPU-Only ■ **PIM-Core** ■ **PIM-Acc**



77.7% and 82.6% of energy reduction for texture tiling and packing comes from eliminating data movement

PIM core and PIM accelerator reduces energy consumption on average by 49.1% and 55.4%

Normalized Runtime

Secondary PIM-Core PIM-Acc



Offloading these kernels to PIM core and PIM accelerator improves performance on average by 44.6% and 54.2%

Conclusion

- Energy consumption is a major challenge in consumer devices
- We conduct an in-depth analysis of popular Google consumer workloads
 - 62.7% of the total system energy is spent on data movement
 - Most of the data movement comes from <u>simple functions</u> that consist of <u>simple operations</u>
- We use **PIM** to reduce data movement cost
 - We design lightweight logic to implement simple operations in DRAM



- Reduces total energy by 55.4% on average
- Reduces execution time by 54.2% on average

Google Workloads for Consumer Devices: Mitigating Data Movement Bottlenecks

Amirali Boroumand

Saugata Ghose, Youngsok Kim, Rachata Ausavarungnirun, Eric Shiu, Rahul Thakur, Daehyun Kim, Aki Kuusela, Allan Knies, Parthasarathy Ranganathan, Onur Mutlu











Google

A Motivating Detour: Genome Sequence Analysis

Our Dream

- An embedded device that can perform comprehensive genome analysis in real time (within a minute)
 - Which of these DNAs does this DNA segment match with?
 - What is the likely genetic disposition of this patient to this drug?

••••

What Is a Genome Made Of?



SAFARI The discovery of DNA's double-helical structure (Watson+, 1953) ⁴⁷⁹

DNA Under Electron Microscope



DNA Sequencing

Goal:

- □ Find the complete sequence of A, C, G, T's in DNA.
- Challenge:
 - There is no machine that takes long DNA as an input, and gives the complete sequence as output
 - All sequencing machines chop DNA into pieces and identify relatively small pieces (but not how they fit together)

Untangling Yarn Balls & DNA Sequencing





Ion Torrent Proton



Complete Genomics





Illumina NovaSeq 6000

Oxford Nanopore GridION

... and more! All produce data with different properties.



Genome Sequence Alignment: Example



Source: By Aaron E. Darling, István Miklós, Mark A. Ragan - Figure 1 from Darling AE, Miklós I, Ragan MA (2008). "Dynamics of Genome Rearrangement in Bacterial Populations". PLOS Genetics. DOI:10.1371/journal.pgen.1000128., CC BY 2.5, https://commons.wikimedia.org/w/index.php?curid=30550950





Hash Table Based Read Mappers

- + Guaranteed to find *all* mappings → sensitive
- + Can tolerate up to *e* errors



http://mrfast.sourceforge.net/

Personalized copy number and segmental duplication maps using next-generation sequencing

Can Alkan^{1,2}, Jeffrey M Kidd¹, Tomas Marques-Bonet^{1,3}, Gozde Aksay¹, Francesca Antonacci¹, Fereydoun Hormozdiari⁴, Jacob O Kitzman¹, Carl Baker¹, Maika Malig¹, Onur Mutlu⁵, S Cenk Sahinalp⁴, Richard A Gibbs⁶ & Evan E Eichler^{1,2}

Alkan+, <u>"Personalized copy number and segmental duplication</u> <u>maps using next-generation sequencing</u>", Nature Genetics 2009.

Read Mapping Execution Time Breakdown



Filter fast before you align

Minimize costly "approximate string comparisons"

Our First Filter: Pure Software Approach

- Download source code and try for yourself
 - Download link to FastHASH

Xin et al. BMC Genomics 2013, **14**(Suppl 1):S13 http://www.biomedcentral.com/1471-2164/14/S1/S13



Open Access

PROCEEDINGS

Accelerating read mapping with FastHASH

Hongyi Xin¹, Donghyuk Lee¹, Farhad Hormozdiari², Samihan Yedkar¹, Onur Mutlu^{1*}, Can Alkan^{3*}

From The Eleventh Asia Pacific Bioinformatics Conference (APBC 2013) Vancouver, Canada. 21-24 January 2013

Shifted Hamming Distance: SIMD Acceleration

Bioinformatics, 31(10), 2015, 1553–1560 doi: 10.1093/bioinformatics/btu856 Advance Access Publication Date: 10 January 2015 Original Paper

OXFORD

Sequence analysis

Shifted Hamming distance: a fast and accurate SIMD-friendly filter to accelerate alignment verification in read mapping

Hongyi Xin^{1,*}, John Greth², John Emmons², Gennady Pekhimenko¹, Carl Kingsford³, Can Alkan^{4,*} and Onur Mutlu^{2,*}

Xin+, <u>"Shifted Hamming Distance: A Fast and Accurate SIMD-friendly Filter</u> to Accelerate Alignment Verification in Read Mapping", Bioinformatics 2015.

An Example Solution: GateKeeper



FPGA-Based Alignment Filtering

 Mohammed Alser, Hasan Hassan, Hongyi Xin, Oguz Ergin, Onur Mutlu, and Can Alkan
"GateKeeper: A New Hardware Architecture for Accelerating Pre-Alignment in DNA Short Read Mapping" *Bioinformatics*, [published online, May 31], 2017.
[Source Code]
[Online link at Bioinformatics Journal]

GateKeeper: a new hardware architecture for accelerating pre-alignment in DNA short read mapping

Mohammed Alser 🖾, Hasan Hassan, Hongyi Xin, Oğuz Ergin, Onur Mutlu 🖾, Can Alkan 🖾

Bioinformatics, Volume 33, Issue 21, 1 November 2017, Pages 3355–3363, https://doi.org/10.1093/bioinformatics/btx342

Published: 31 May 2017 Article history •

DNA Read Mapping & Filtering

- Problem: Heavily bottlenecked by Data Movement
- GateKeeper FPGA performance limited by DRAM bandwidth [Alser+, Bioinformatics 2017]
- Ditto for SHD on SIMD [Xin+, Bioinformatics 2015]
- Solution: Processing-in-memory can alleviate the bottleneck
- However, we need to design mapping & filtering algorithms to fit processing-in-memory

In-Memory DNA Sequence Analysis

 Jeremie S. Kim, Damla Senol Cali, Hongyi Xin, Donghyuk Lee, Saugata Ghose, Mohammed Alser, Hasan Hassan, Oguz Ergin, Can Alkan, and Onur Mutlu,
"GRIM-Filter: Fast Seed Location Filtering in DNA Read Mapping Using Processing-in-Memory Technologies"

BMC Genomics, 2018. *Proceedings of the <u>16th Asia Pacific Bioinformatics Conference</u> (APBC), Yokohama, Japan, January 2018. <u>arxiv.org Version (pdf)</u>*

GRIM-Filter: Fast seed location filtering in DNA read mapping using processing-in-memory technologies

Jeremie S. Kim^{1,6*}, Damla Senol Cali¹, Hongyi Xin², Donghyuk Lee³, Saugata Ghose¹, Mohammed Alser⁴, Hasan Hassan⁶, Oguz Ergin⁵, Can Alkan^{4*} and Onur Mutlu^{6,1*}

From The Sixteenth Asia Pacific Bioinformatics Conference 2018 Yokohama, Japan. 15-17 January 2018

Quick Note: Key Principles and Results

- Two key principles:
 - Exploit the structure of the genome to minimize computation
 - Morph and exploit the structure of the underlying hardware to maximize performance and efficiency
- Algorithm-architecture co-design for DNA read mapping
 - Speeds up read mapping by ~200X (sometimes more)
 - Improves accuracy of read mapping in the presence of errors

Xin et al., "Accelerating Read Mapping with FastHASH," BMC Genomics 2013. Xin et al., "Shifted Hamming Distance: A Fast and Accurate SIMD-friendly Filter to Accelerate Alignment Verification in Read Mapping," Bioinformatics 2015. Alser et al., "GateKeeper: A New Hardware Architecture for Accelerating Pre-Alignment in DNA Short Read Mapping," Bioinformatics 2017. Kim et al., "Genome Read In-Memory (GRIM) Filter," BMC Genomics 2018.

New Genome Sequencing Technologies

Nanopore sequencing technology and tools for genome assembly: computational analysis of the current state, bottlenecks and future directions

Damla Senol Cali 🖾, Jeremie S Kim, Saugata Ghose, Can Alkan, Onur Mutlu

Briefings in Bioinformatics, bby017, https://doi.org/10.1093/bib/bby017 Published: 02 April 2018 Article history ▼



Oxford Nanopore MinION

Senol Cali+, "Nanopore Sequencing Technology and Tools for Genome Assembly: Computational Analysis of the Current State, Bottlenecks and Future Directions," Briefings in Bioinformatics, 2018. [Preliminary arxiv.org version]

Nanopore Genome Assembly Pipeline



Figure 1. The analyzed genome assembly pipeline using nanopore sequence data, with its five steps and the associated tools for each step. Senol Cali+, "Nanopore Sequencing Technology and Tools for Genome

SAFARI Assembly," Briefings in Bioinformatics, 2018.

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Accelerating Genome Analysis A Primer on an Ongoing Journey

Onur Mutlu <u>omutlu@gmail.com</u> <u>https://people.inf.ethz.ch/omutlu</u> May 21, 2018

HiCOMB-17 Keynote Talk

Systems @ ETH zurich

SAFARI

ETH zürich

- An embedded device that can perform comprehensive genome analysis in real time (within a minute)
- Still a long ways to go
 - Energy efficiency
 - Performance (latency)
 - Security
 - Huge memory bottleneck

End of Backup Slides

- Onur Mutlu
 - □ Full Professor @ ETH Zurich CS, since September 2015
 - Strecker Professor @ Carnegie Mellon University ECE/CS, 2009-2016, 2016-...
 - □ PhD from UT-Austin, worked at Google, VMware, Microsoft Research, Intel, AMD
 - https://people.inf.ethz.ch/omutlu/
 - omutlu@gmail.com (Best way to reach me)
 - https://people.inf.ethz.ch/omutlu/projects.htm
- Research and Teaching in:
 - Computer architecture, computer systems, hardware security, bioinformatics
 - Memory and storage systems
 - Hardware security, safety, predictability
 - Fault tolerance
 - Hardware/software cooperation
 - Architectures for bioinformatics, health, medicine

• ...

Current Research Focus Areas





Graphics and Vision Processing

Four Key Directions

Fundamentally Secure/Reliable/Safe Architectures

Fundamentally Energy-Efficient Architectures
Memory-centric (Data-centric) Architectures

Fundamentally Low-Latency Architectures

Architectures for Genomics, Medicine, Health